

Term 7- Sept 2025

Nanoelectronics and Technology
(01.119/99.503)-Week 2 Class 1

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23-Sept- 2025

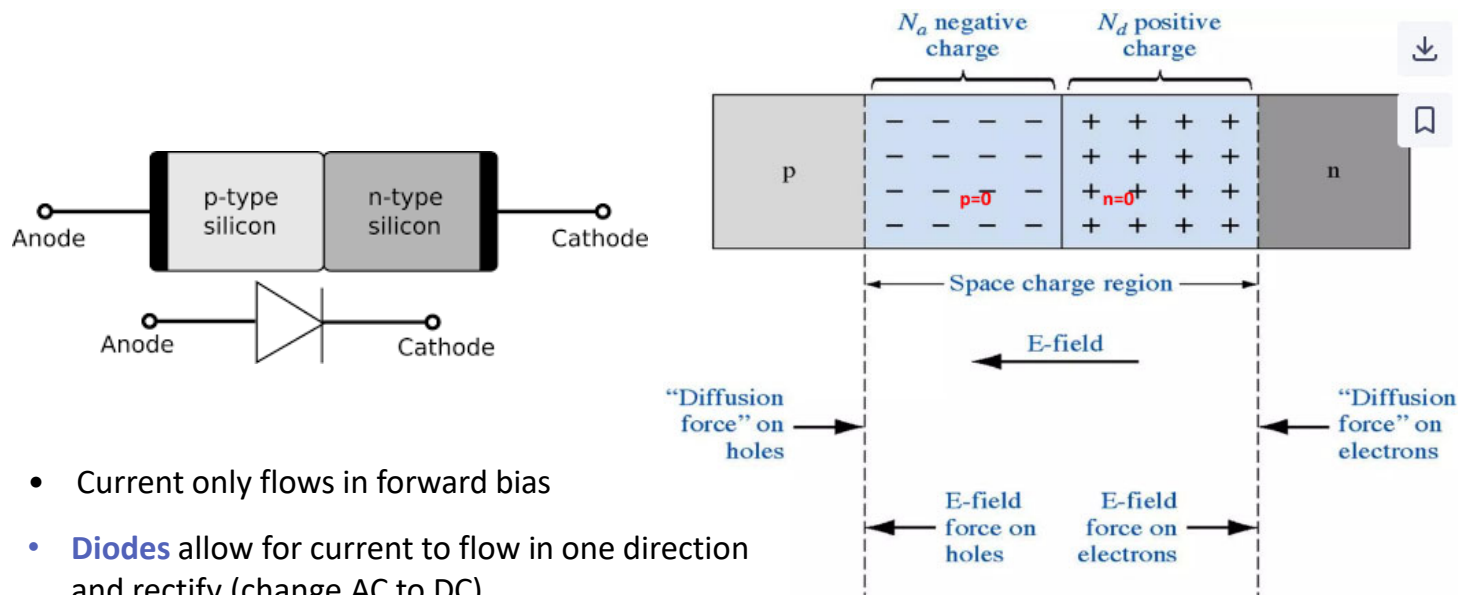
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Outline

- Schottky Diodes
- Ohmic contact
- Introduction to MOS structure
- MOSFET structure

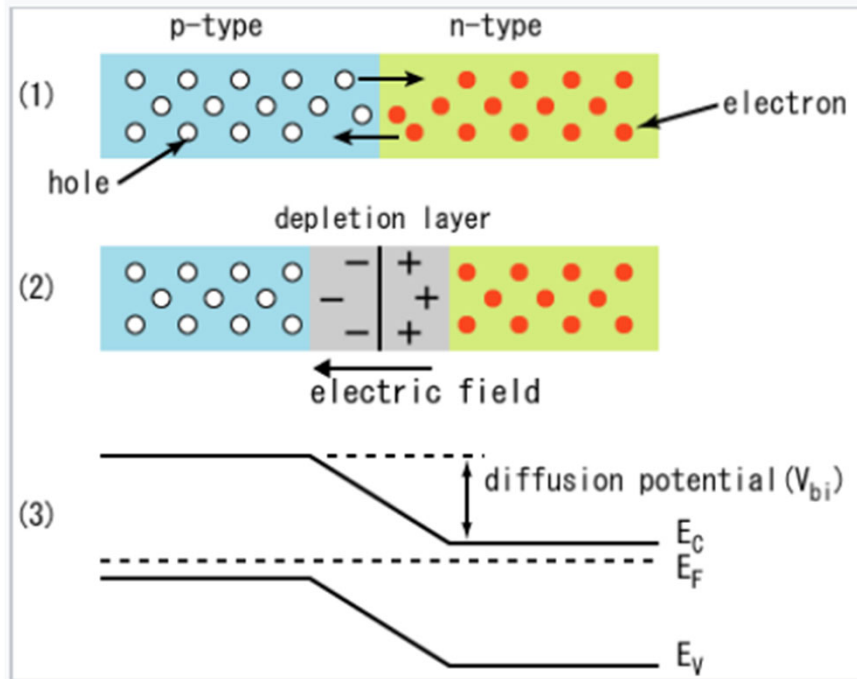
P-N Junction (Diode)

A p-n junction diode is a basic semiconductor device that controls the flow of electric current in a circuit. It has a positive (p) side and a negative (n) side created by adding impurities to each side of a silicon semiconductor.

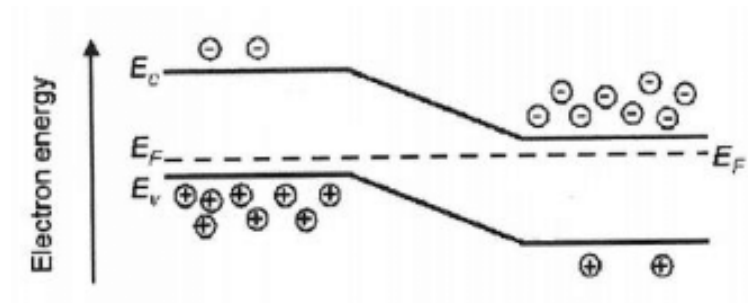


<https://www.slideshare.net/slideshow/p-n-junctioneema/68227503>

P-N Junction (Diode)-Built in potential

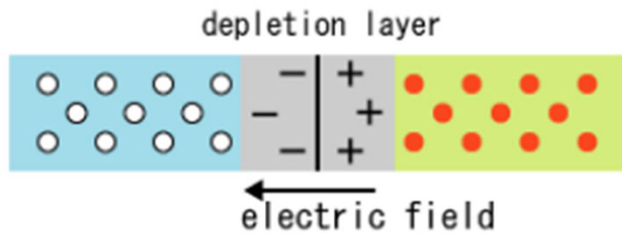


The built-in potential of a P-N junction is the potential difference that develops at the intersection of its p-type semiconductor material and n-type semiconductor material. This built-in potential develops in the depletion region.

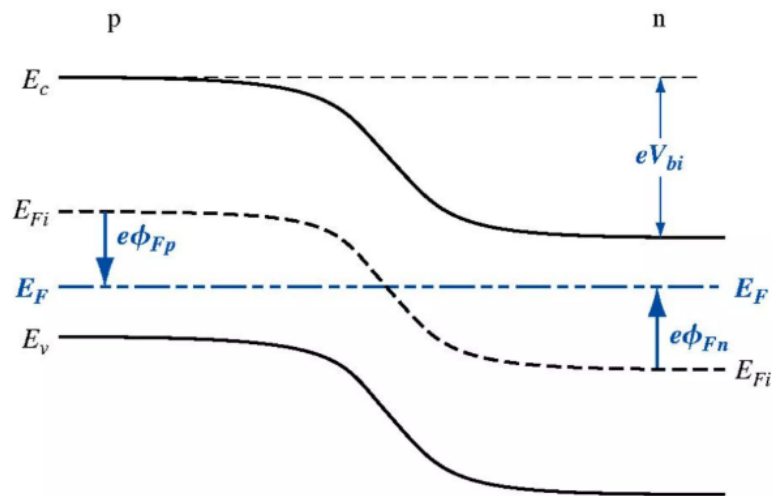


<https://study.com/academy/lesson/p-n-junction-diode-definition-properties.html>

P-N Junction (Diode)-Built in potential



The built-in potential of a P-N junction is the potential difference that develops at the intersection of its p-type semiconductor material and n-type semiconductor material. This built-in potential develops in the depletion region.



$$\phi_{bi} = \frac{kT}{q} \ln \frac{N_d N_a}{n_i^2}$$

Formula

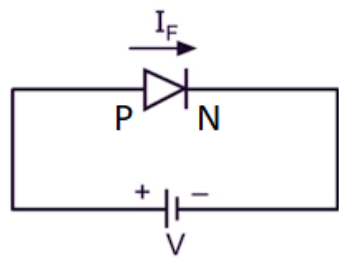
PN Junction Built-in Potential

$$V_{\text{built-in}} = \frac{kT}{q} \ln \left(\frac{N_D N_A}{n_i^2} \right)$$

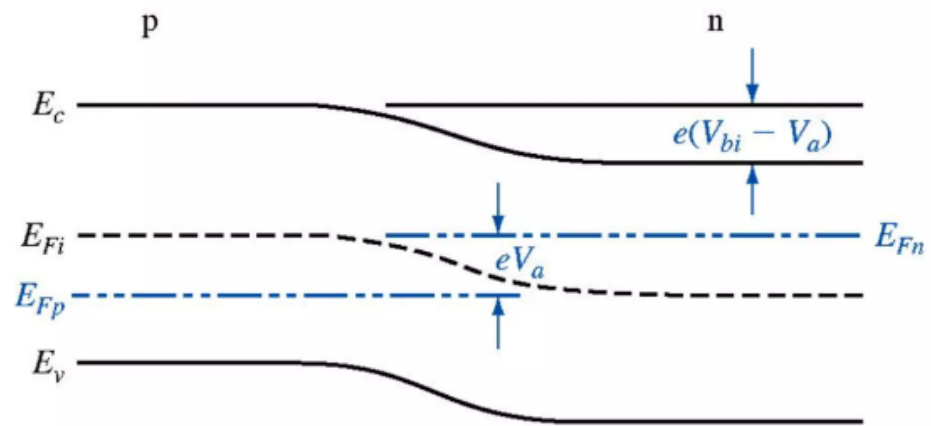
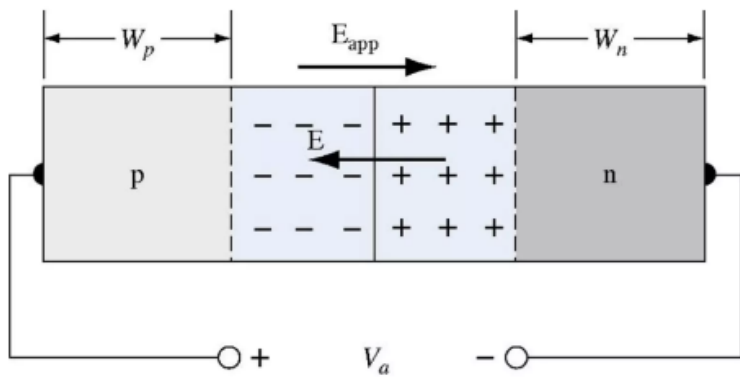
$V_{\text{built-in}}$	→ Built-in potential in volts
N_D	→ n type - donor atoms concentration
N_A	→ p type - acceptor atoms concentration
n	→ concentration of electrons
kT/q	→ thermal voltage
T	→ temperature in Kelvin
q	→ charges in coulombs

P-N Junction (Diode)-Forward Bias

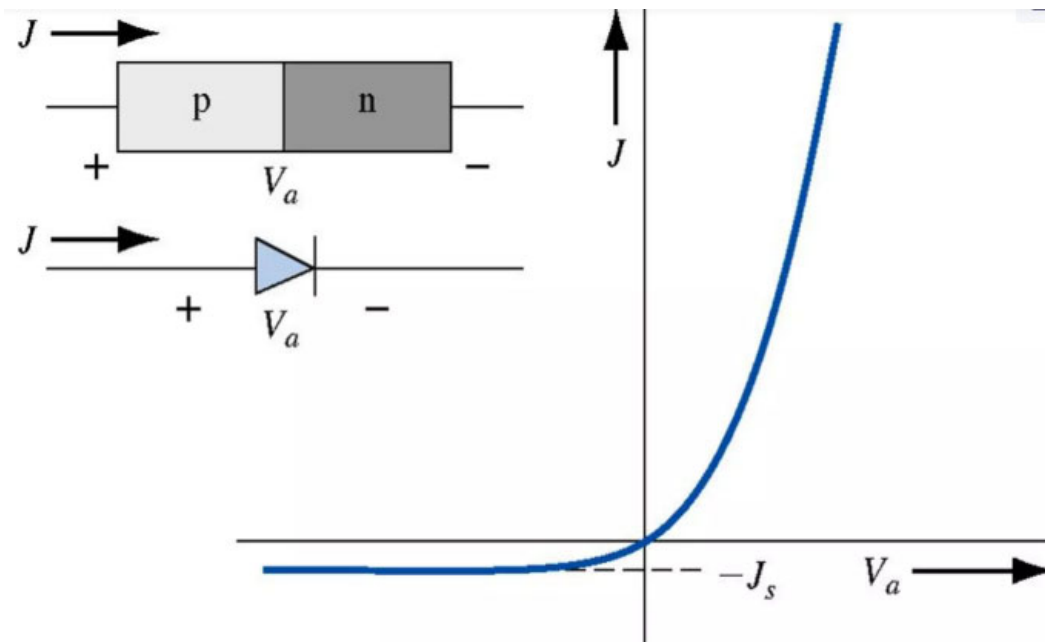
When positive terminal of the source is connected to the P side and the negative terminal is connected to N side then the junction diode is said to be connected in forward bias condition.



FORWARD BIAS PN JUNCTION

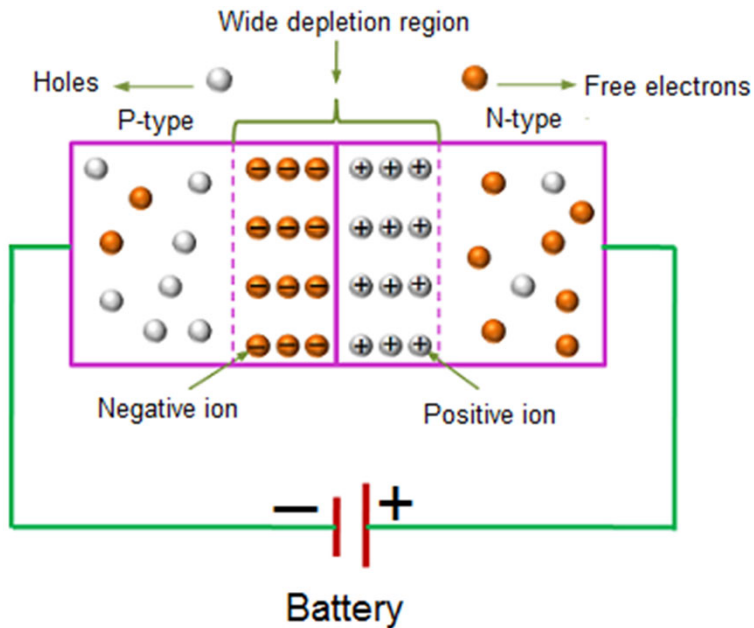


P-N Junction (Diode)-Forward Bias



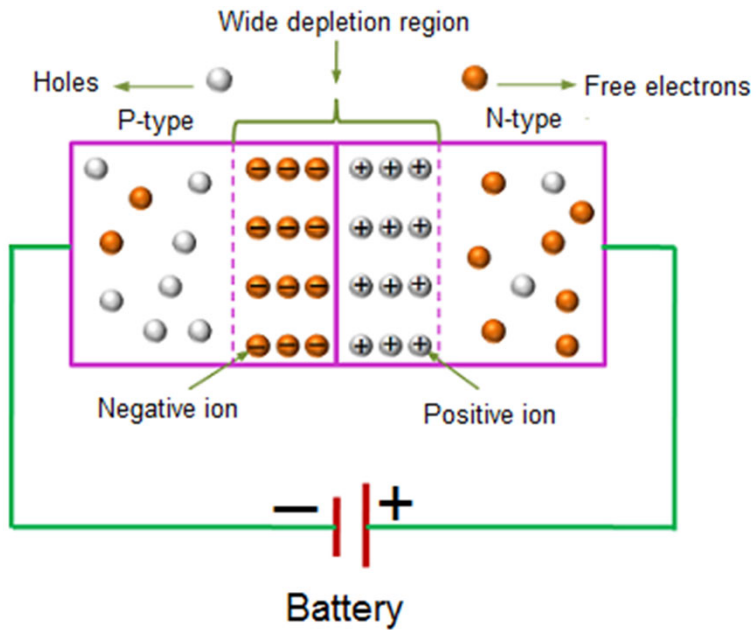
$$J \approx J_s \left[\exp \left(\frac{eV_a}{kT} \right) - 1 \right]$$

P-N Junction (Diode)-Reverse Bias

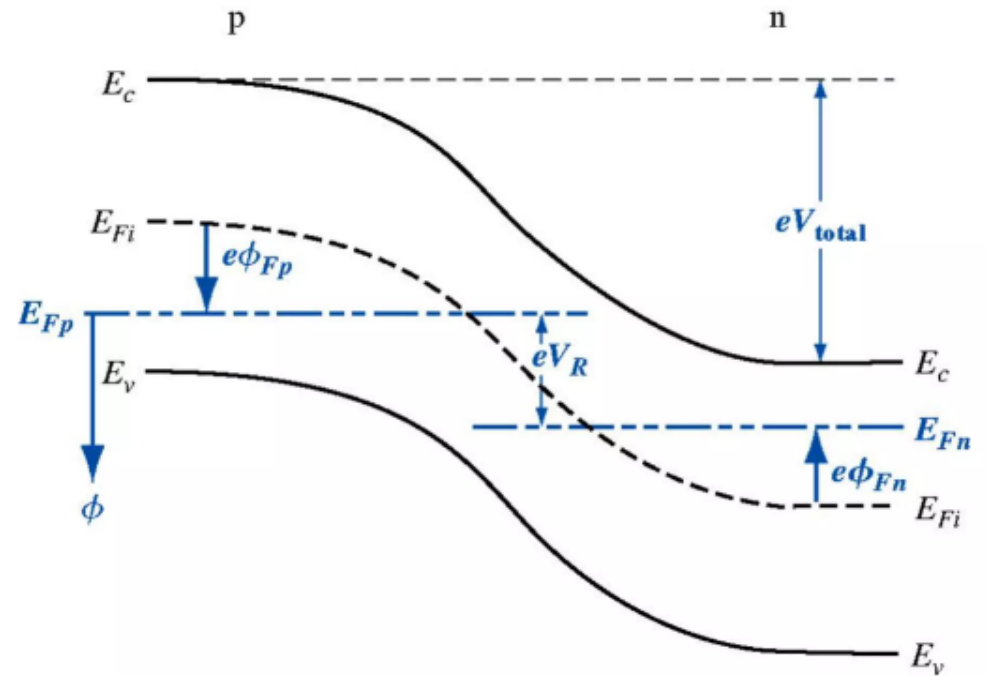


- Positive terminal attracts the electrons away from the junction in N side and negative terminal attracts the holes away from the junction in P side.
- As a result of it, the width of the potential barrier increases that impedes the flow of majority carriers in N side and P side.

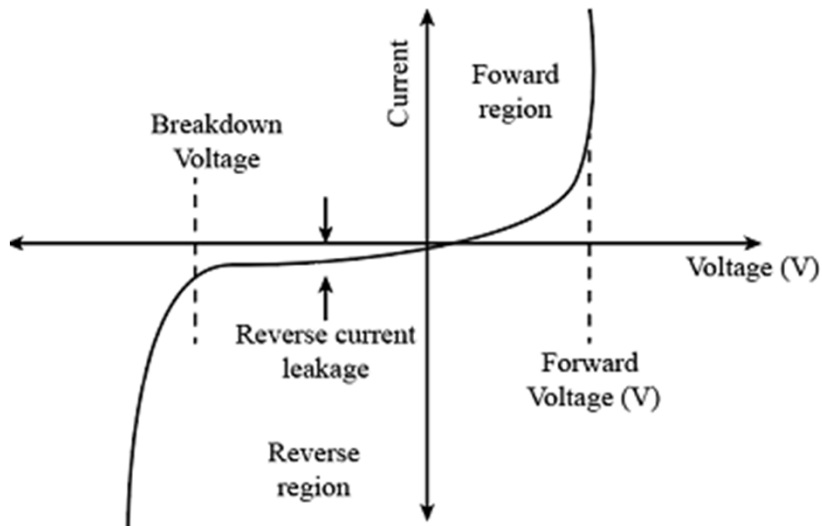
P-N Junction (Diode)-Reverse Bias



BAND diagram of REVERSE BIAS PN JUNCTION



P-N Junction (Diode)-Reverse Bias



Breakdown occurs by two mechanisms.

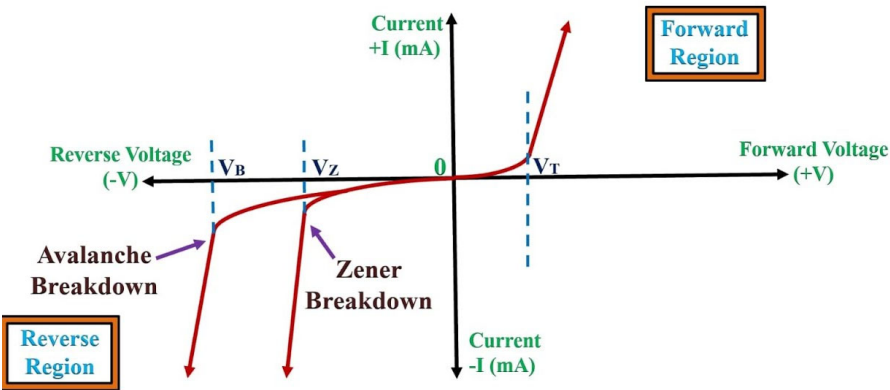
(A) Zener Breakdown (Low Reverse Voltage, $< \sim 5\text{--}6\text{ V}$)

- Occurs in **heavily doped PN junctions** (narrow depletion region).
- Strong **electric field** develops across the narrow depletion layer.
- This field is strong enough to **break covalent bonds** and cause **quantum mechanical tunneling** of electrons from the valence band (P-side) into the conduction band (N-side).
- Result \rightarrow sudden increase in current.
- Dominant in **low-voltage Zener diodes**.

P-N Junction (Diode)-Reverse Bias

Breakdown occurs by two mechanisms.

Avalanche and Zener Breakdown



(A) Zener Breakdown (Low Reverse Voltage, $< \sim 5-6$ V)

- Occurs in **heavily doped PN junctions** (narrow depletion region).
- Strong **electric field** develops across the narrow depletion layer.
- This field is strong enough to **break covalent bonds** and cause **quantum mechanical tunneling** of electrons from the valence band (P-side) into the conduction band (N-side).
- Result \rightarrow sudden increase in current.
- Dominant in **low-voltage Zener diodes**.

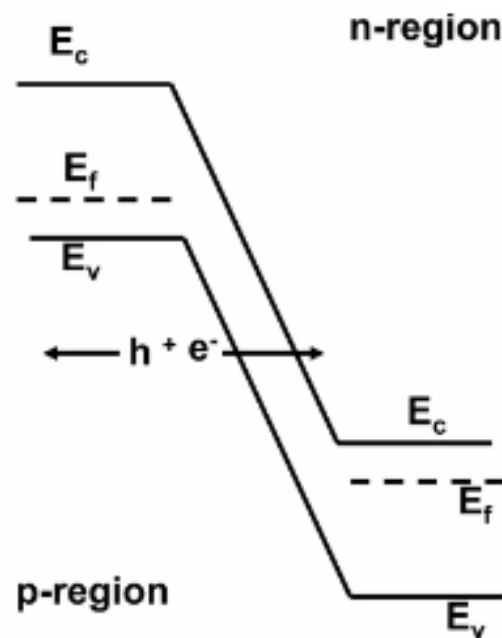
(B) Avalanche Breakdown (Higher Reverse Voltage, $> \sim 6$ V)

- Occurs in **lightly doped PN junctions** (wide depletion region).
- Minority carriers (electrons/holes) accelerated by the strong electric field gain enough energy to **ionize atoms** when they collide with the lattice.
- This generates **new electron-hole pairs**, which are again accelerated \rightarrow **chain reaction (avalanche multiplication)**.
- Result \rightarrow sharp rise in current.
- Dominant in **power diodes and high-voltage junctions**.

P-N Junction (Diode)-Reverse Bias

Zener Breakdown : Heavily doped junction

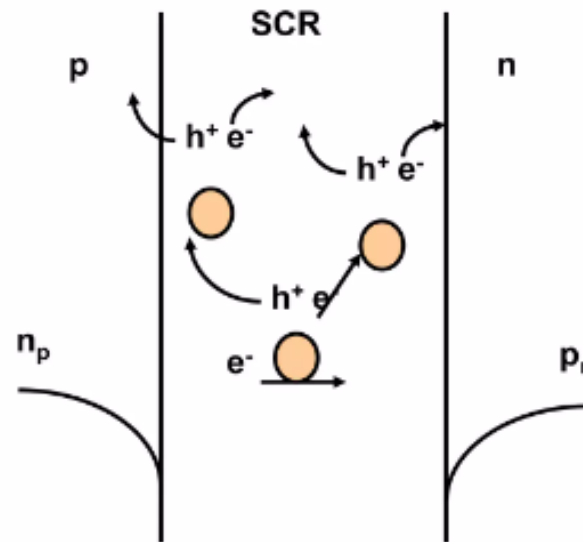
- the valence band edge of p-region will be at a higher potential than the conduction band edge of the n-region. Due to heavy doping depletion layer will be thin.
- Breakdown occurs due to electron tunneling between the valence band of the p-region and conduction band of the n-region. A large reverse current flows. This is known as **Zener Breakdown**.



P-N Junction (Diode)-Reverse Bias

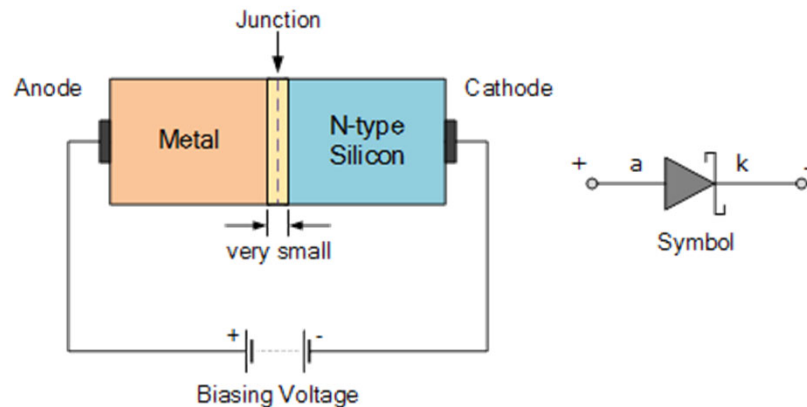
Avalanche Breakdown : in high electric field

- Electrons or holes traveling inside the SCR attain high velocity when reverse bias is high and collide with atoms dislodging an electron from the atom and causing an electron-hole pair to form, the process continues.
- This is known as **Avalanche multiplication**, resulting in a large reverse bias current leading to breakdown



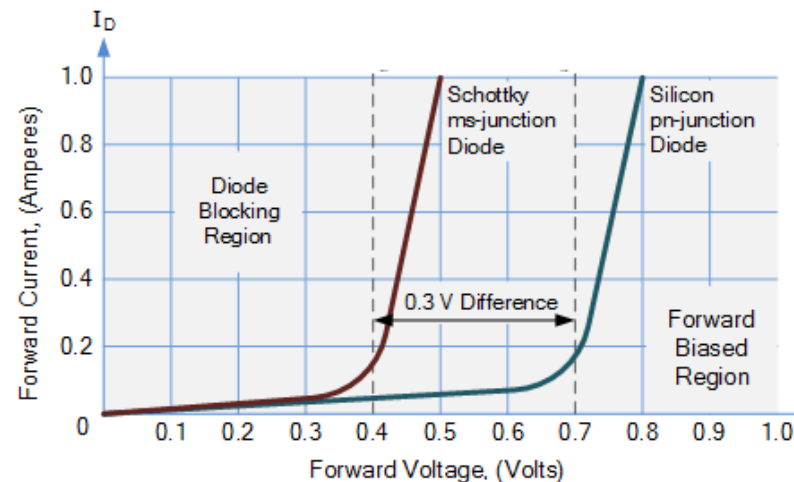
Schottky Diode: Metal-Semiconductor Junction

- The Schottky diode is a semiconductor diode formed by the junction of a semiconductor (N-type) with a metal.
- Current conduction is mainly due to **majority carriers** (usually electrons from the N-type side).
- It has a low forward voltage drop and a very fast switching action.
- The most common contact metal used for Schottky diode construction is “Silicide” which is a highly conductive silicon and metal compound.



<https://www.electronics-tutorials.ws/diode/schottky-diode.html>

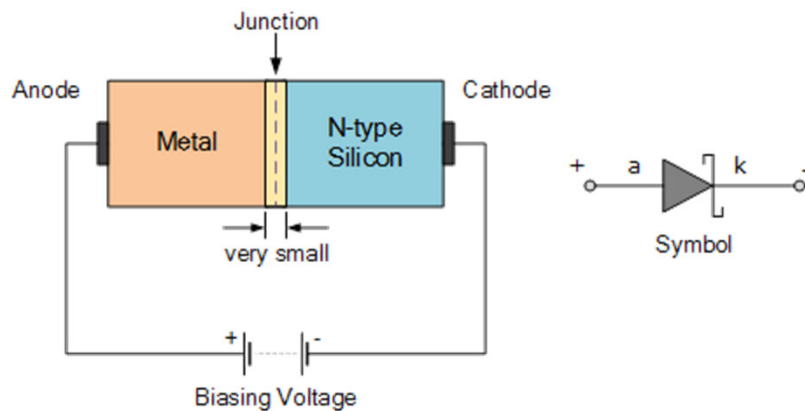
Schottky Diode IV-Characteristics



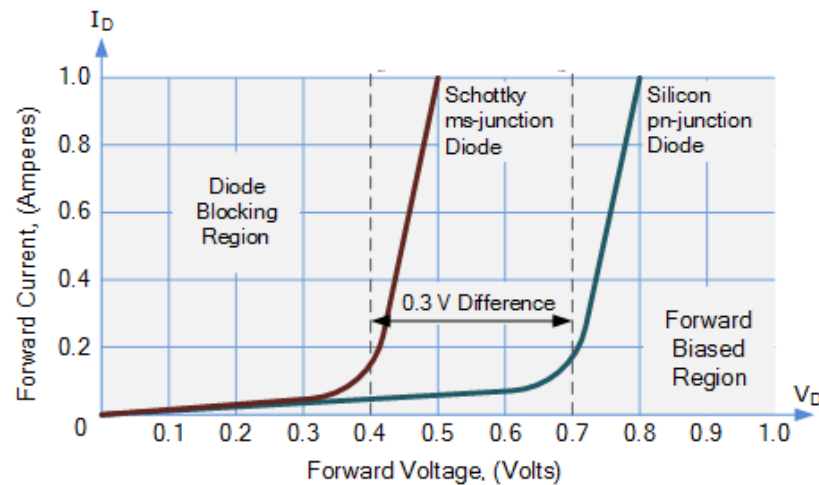
Schottky Diode: Metal-Semiconductor Junction

Barrier Potential

- **PN Diode:** Has a barrier potential of about **0.7 V (Si)**.
- **Schottky Diode:** Has a much lower barrier potential, typically **0.2–0.3 V**, because it is a metal–semiconductor junction.



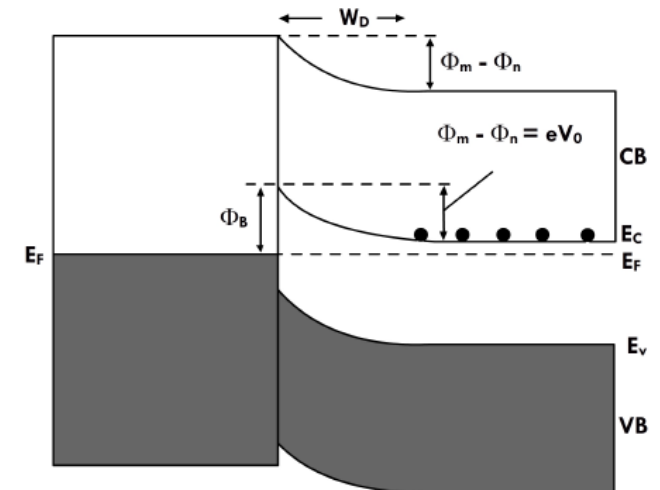
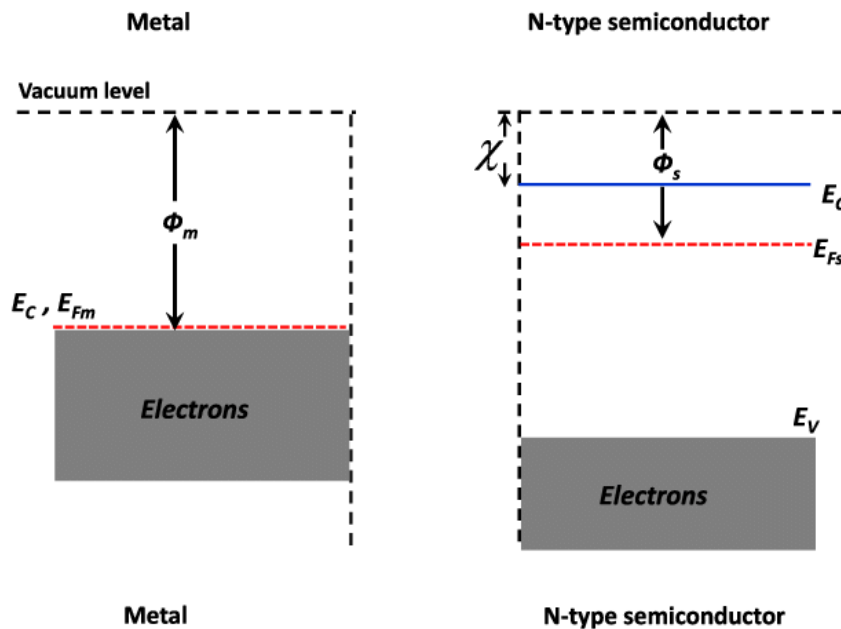
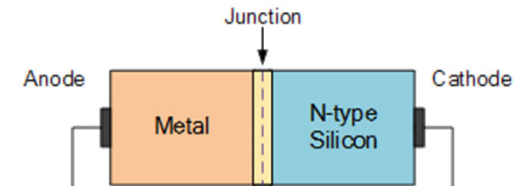
Schottky Diode IV-Characteristics



<https://www.electronics-tutorials.ws/diode/schottky-diode.html>

Schottky Diode: Metal-Semiconductor Junction

- A Schottky junction is formed when the semiconductor has a lower work function than the metal.

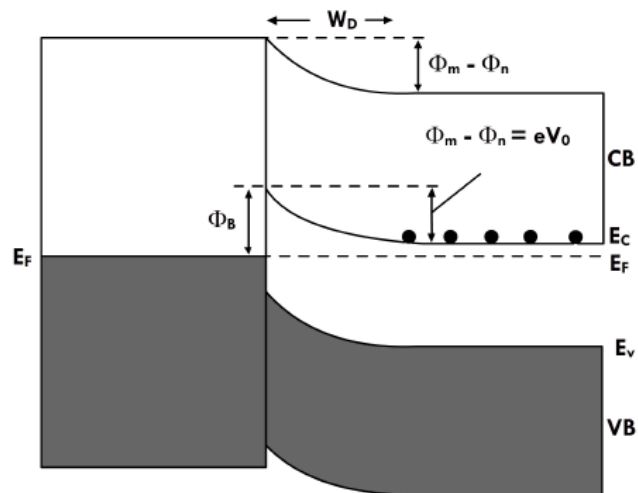
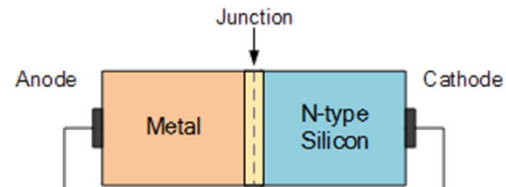


Equilibrium condition

<https://www.electronics-tutorials.ws/diode/schottky-diode.html>

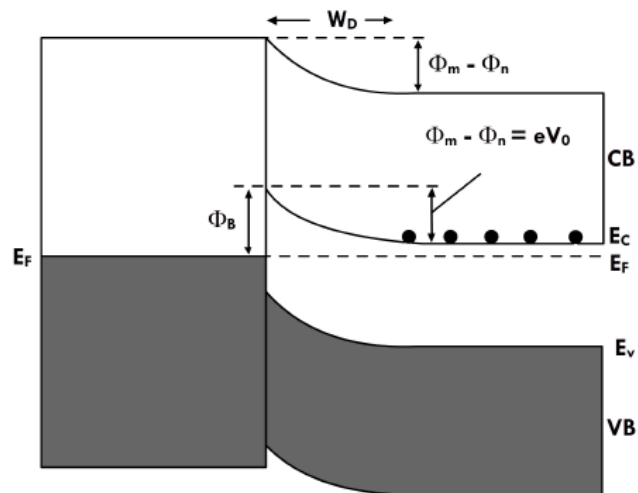
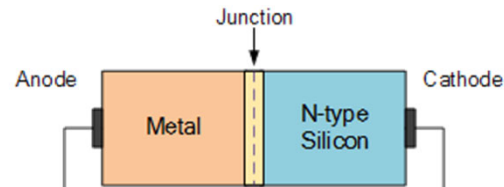
<https://www.icrfq.net/schottky-diode/>

Schottky Diode: Metal-Semiconductor Junction

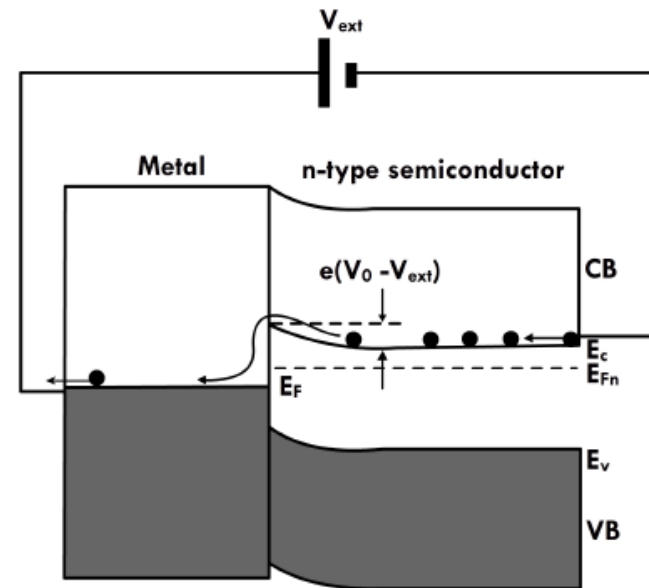


Equilibrium condition

Schottky Diode: Metal-Semiconductor Junction (Forward Bias)

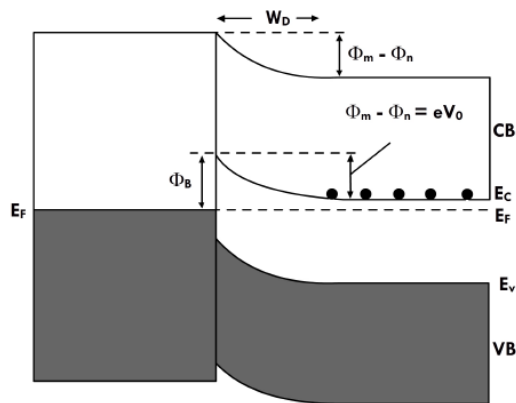
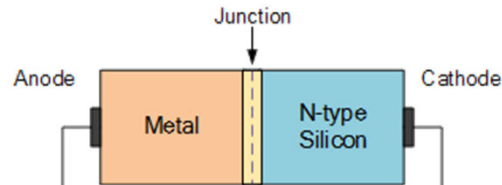


Equilibrium condition

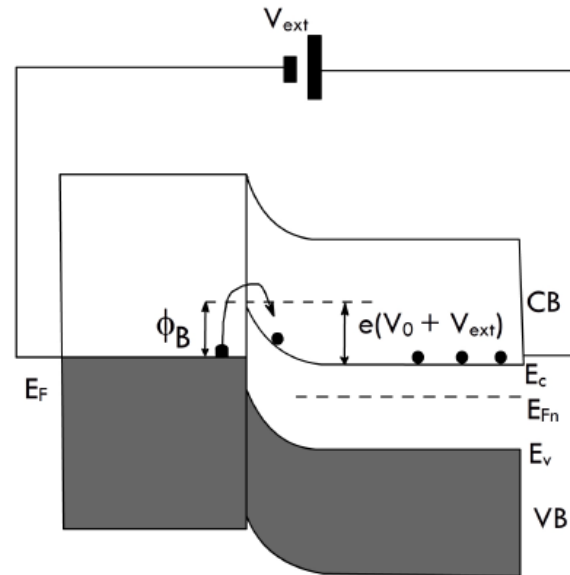


Forward Bias

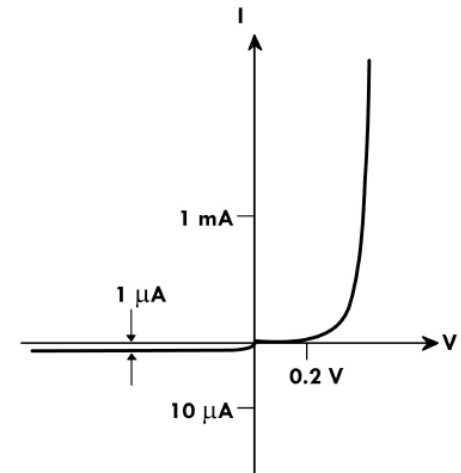
Schottky Diode: Metal-Semiconductor Junction (Reverse Bias)



Equilibrium condition



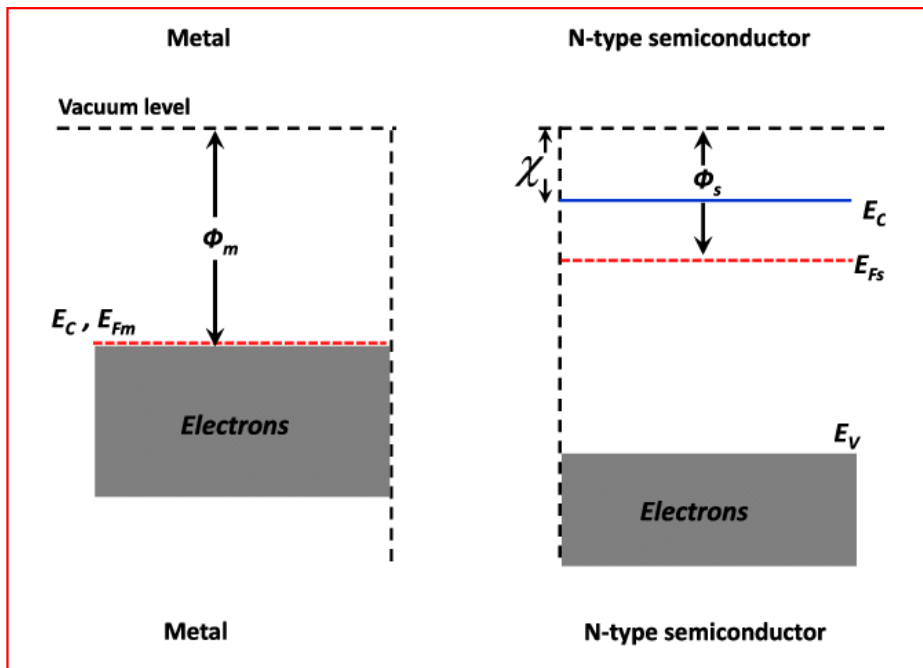
Reverse Bias



Ohmic Contact

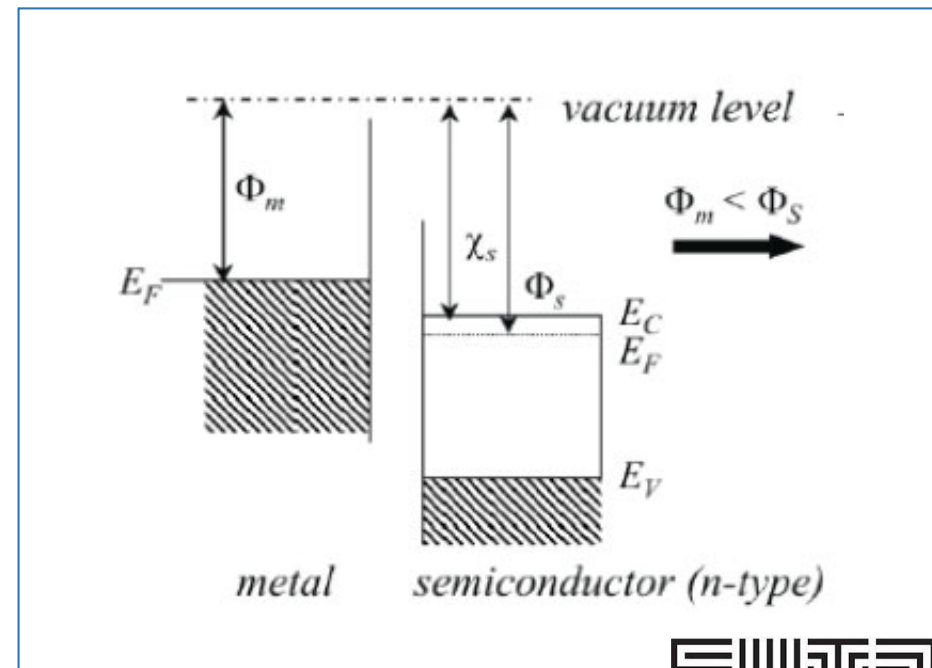
- A Schottky junction is formed when the semiconductor has a lower work function than the metal. When the semiconductor has a higher work function the junction formed is called the Ohmic junction.

Schottky junction



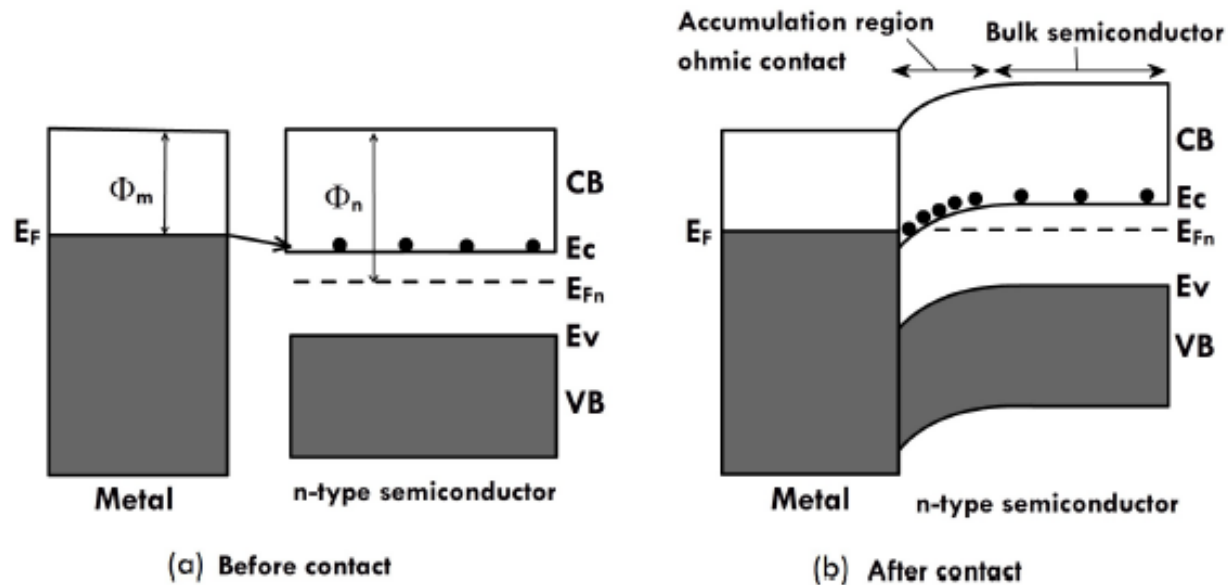
<https://www.icrfq.net/schottky-diode/>

Ohmic junction



Ohmic Contact

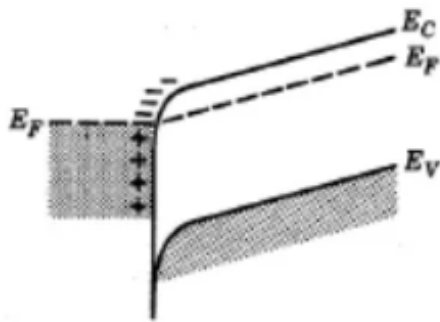
- A Schottky junction is formed when the semiconductor has a lower work function than the metal. When the semiconductor has a higher work function the junction formed is called the Ohmic junction.
- Ohmic junction behaves as a resistor conducting in both forward and reverse bias. The resistivity is determined by the bulk resistivity of the semiconductor.



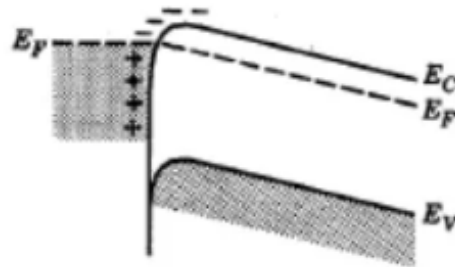
Ohmic Contact

Ohmic Contact (Forward bias and Reverse Bias)

Forward Bias ($V_A > 0V$)



Reverse Bias ($V_A < 0V$)



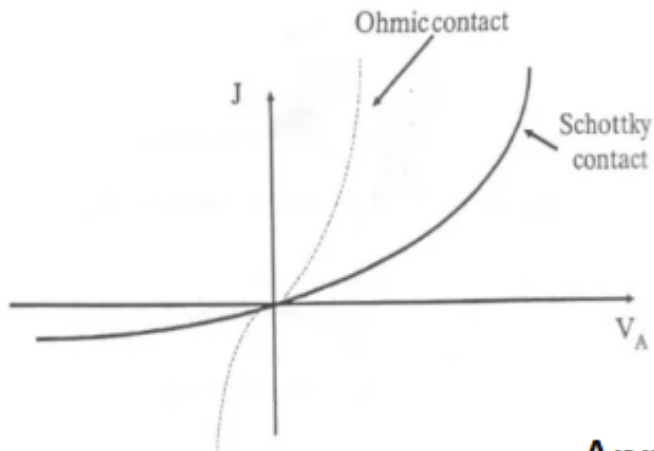
Heavy doping near the junction (degenerate semiconductor):
High doping narrows the depletion region, enabling **tunneling** of carriers
→ ohmic behavior even if a barrier exists.

- When bias is applied, practically all applied voltage drops across the higher resistance region which is the bulk neutral semiconductor.
- Current is therefore determined by the resistance of the bulk, ie. measures property of device

- no depletion region
- **accumulation of majority carriers** near the semiconductor surface
- low resistance to current flow
- non-rectifying □ ohmic

Ohmic Contact (Forward bias and Reverse Bias)

Current-Voltage Characteristics



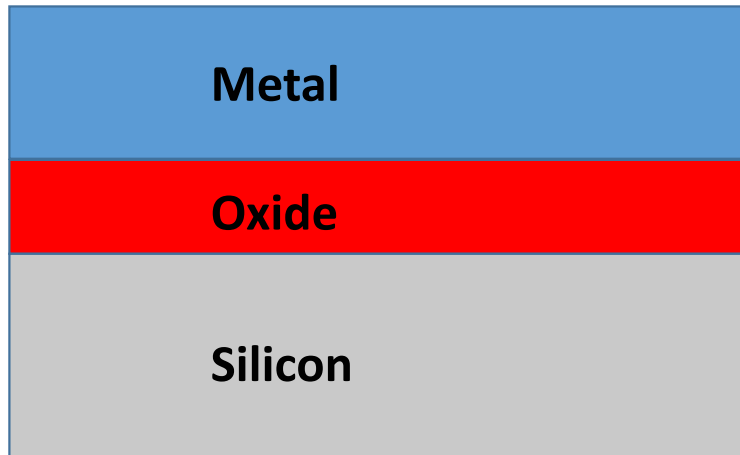
Some discussions:

- Ohmic contacts have large current in both directions
- Typically, the resistance is very small
- Since the contact resistance is very small, the voltage will be dropped on the semiconductor

Applications

- Ohmic contacts are essential in **all semiconductor devices** (diodes, transistors, ICs).
- They provide the **electrical connection between metal electrodes and the semiconductor regions** (e.g., source, drain, emitter, collector).
- Without ohmic contacts, devices would behave like diodes at their terminals instead of allowing proper current injection.

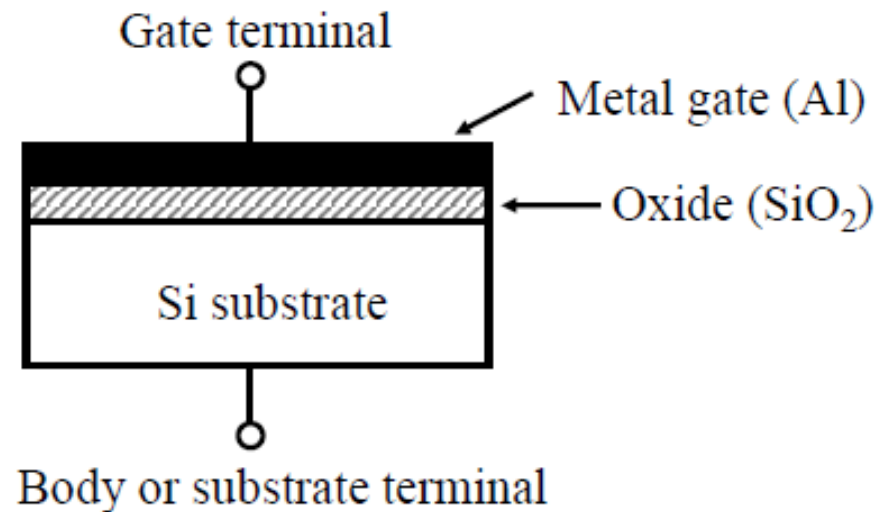
MOS structures



- Accumulation mode
- Depletion mode
- Inversion mode

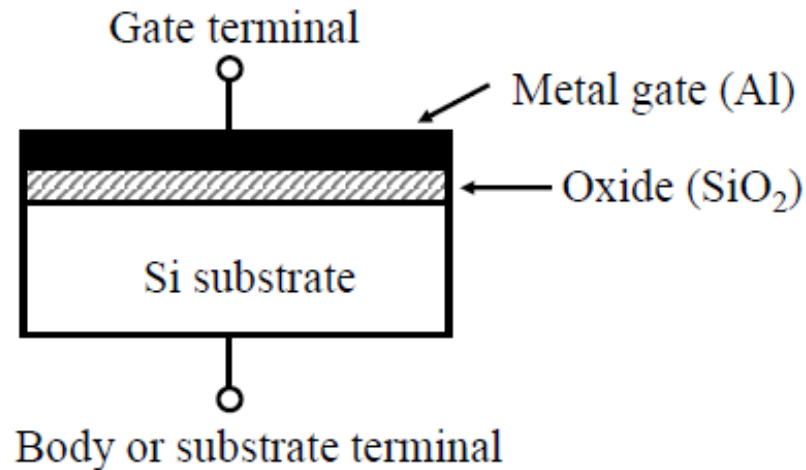
MOS Capacitor

- MOS: Metal-oxide-semiconductor
 - Gate: metal (or polysilicon)
 - Oxide: silicon dioxide, grown on substrate
- MOS capacitor: two-terminal MOS structure



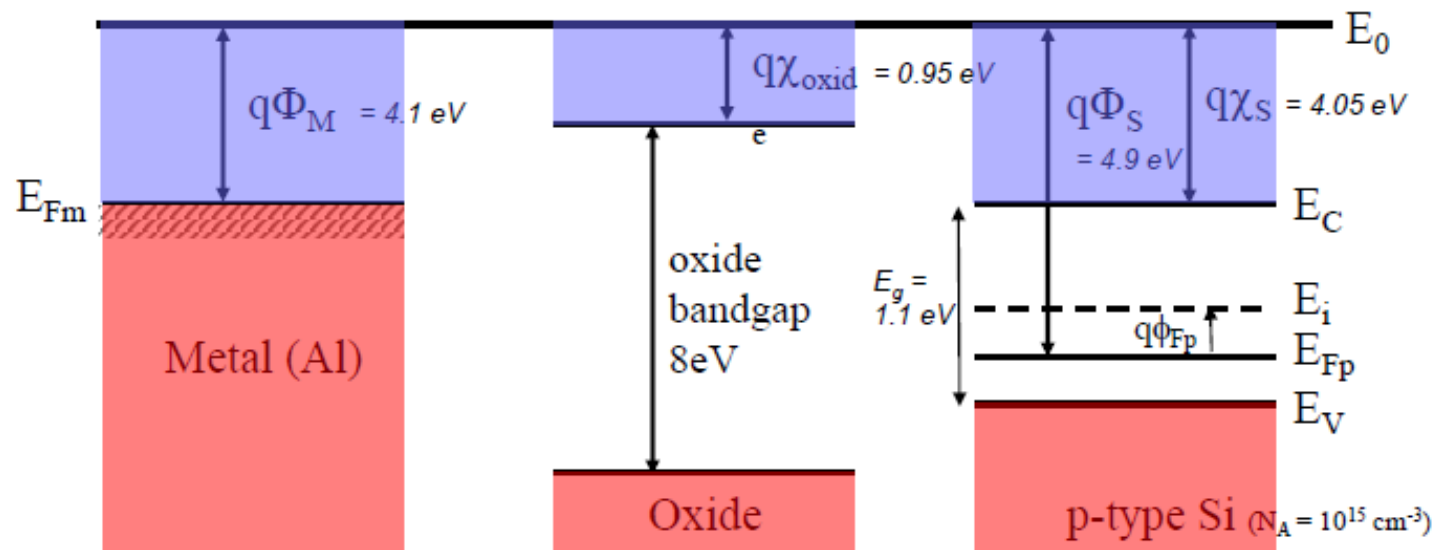
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MOS Capacitors

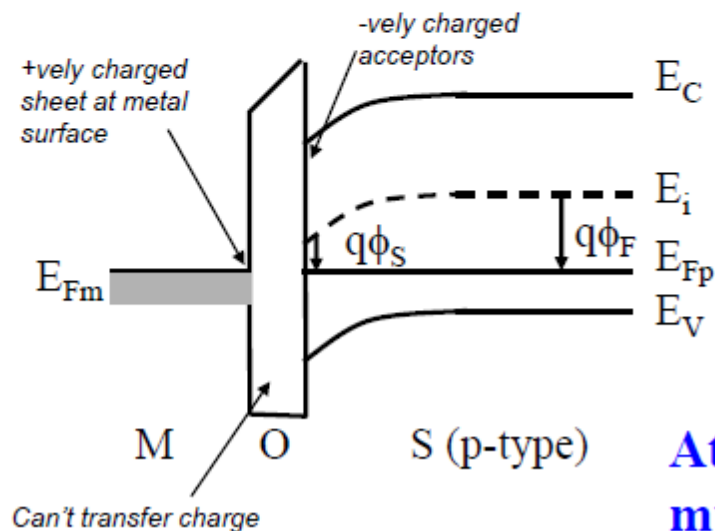
MOS Energy Band Diagram



- Work function ($q\Phi_M$, $q\Phi_S$): energy required to take electron from Fermi level to free space
- Work function difference between Al and Si = 0.8 V

MOS Capacitors- Energy band diagram

- Bands must bend for Fermi levels to line up
- Amount of bending is equal to work function difference: $q\Phi_M - q\Phi_S$
- Fermi levels equalized by transfer of -ve charge from materials with higher E_F (smaller work functions) across interfaces to materials with lower E_F
- Part of voltage drop occurs across oxide, rest occurs next to O-S interface



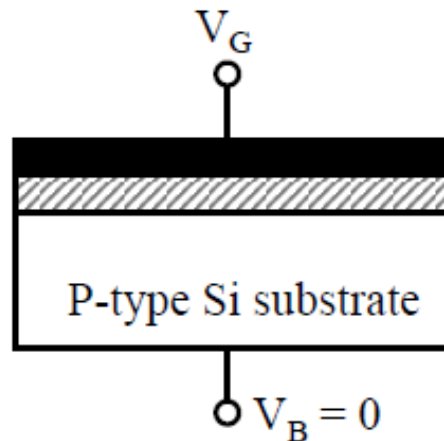
ϕ_F = Fermi potential
(difference between E_F
and E_i in bulk)

ϕ_s = surface potential

**At equilibrium, Fermi levels
must line up!!**

MOS Capacitors- Operation

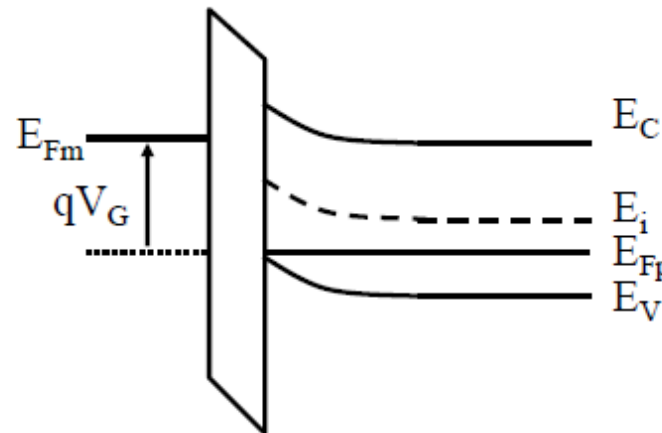
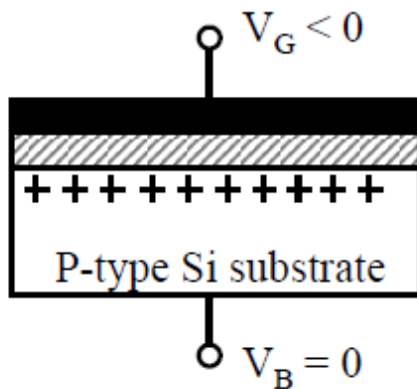
- Assume p-type substrate
- Three regions of operation
 - Accumulation ($V_G < 0$)
 - Depletion ($V_G > 0$ but small)
 - Inversion ($V_G \gg 0$)



MOS Capacitors- Operation

Accumulation

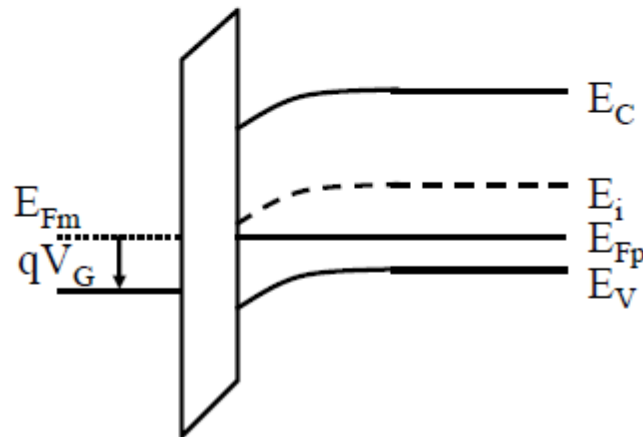
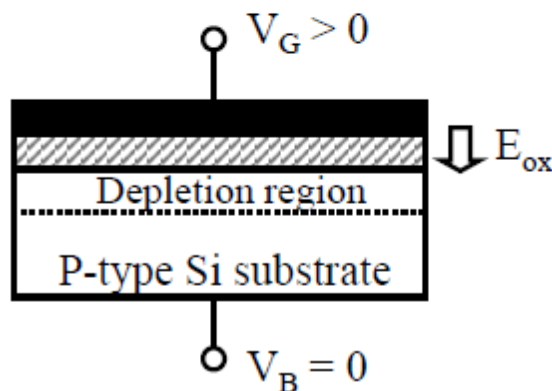
- Negative voltage on gate: attracts holes in substrate towards oxide
- Holes “accumulate” on Si surface (surface is more strongly p-type)
- Electrons pushed deeper into substrate



MOS Capacitors- Operation

Depletion

- Positive voltage on gate: repels holes in substrate
 - Holes leave behind negatively charged acceptor ions
- Depletion region forms: devoid of carriers
 - Electric field directed from gate to substrate
- Bands bend downwards near surface
 - Surface becomes less strongly p-type (E_F close to E_i)

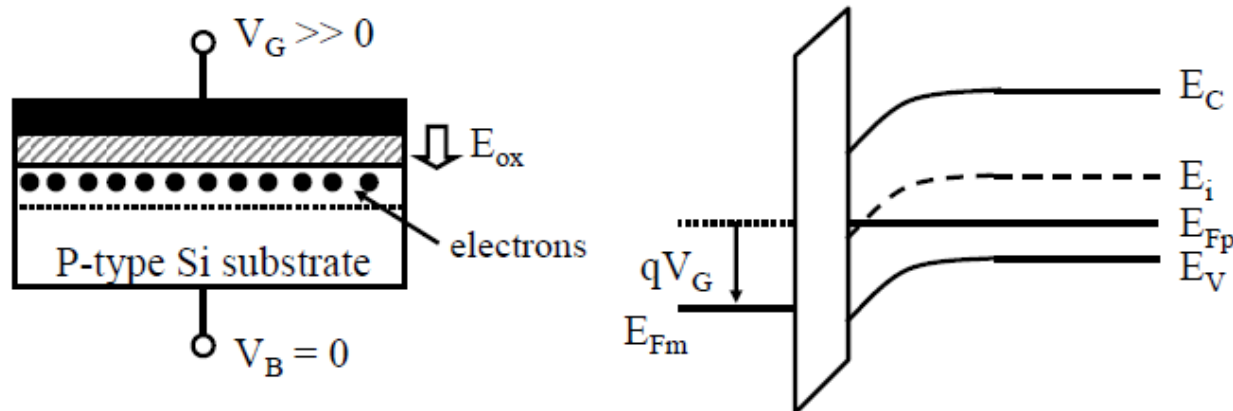


MOS Capacitors- Operation

Inversion

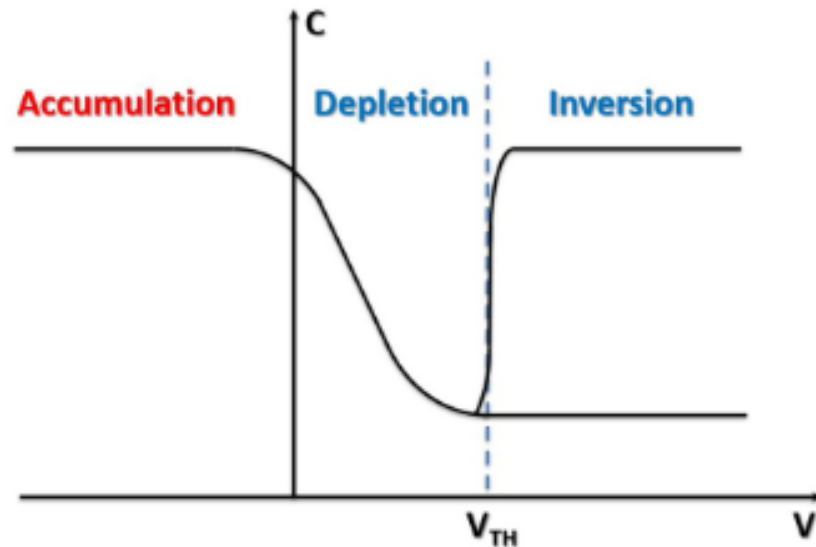
- Increase voltage on gate, bands bend more
- Additional minority carriers (electrons) attracted from substrate to surface
 - Forms “inversion layer” of electrons
- Surface becomes n-type

$$V_t = V_{fb} + 2\phi_B + \frac{\sqrt{qN_a2\epsilon_s2\phi_B}}{C_{ox}}$$



MOS Capacitors- C-V Characteristics

C-V Characteristics

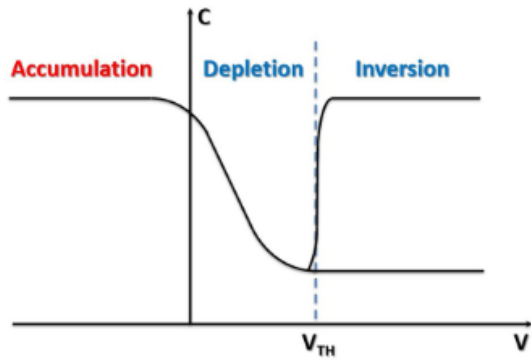


$$C_{dep} = \frac{\epsilon_s}{W_{dep}}$$

$$\frac{1}{C} = \frac{1}{C_{ox}} + \frac{1}{C_{dep}}$$

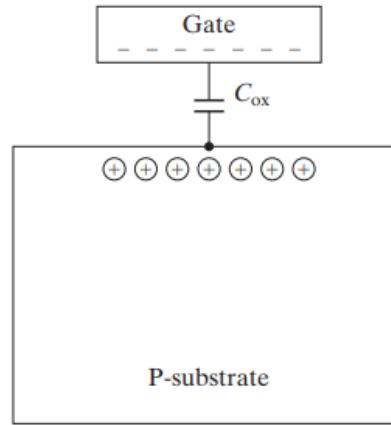
MOS Capacitors- C-V Characteristics

C-V Characteristics

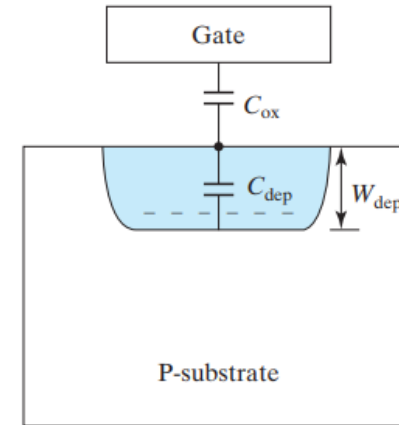


$$C_{dep} = \frac{\epsilon_s}{W_{dep}}$$

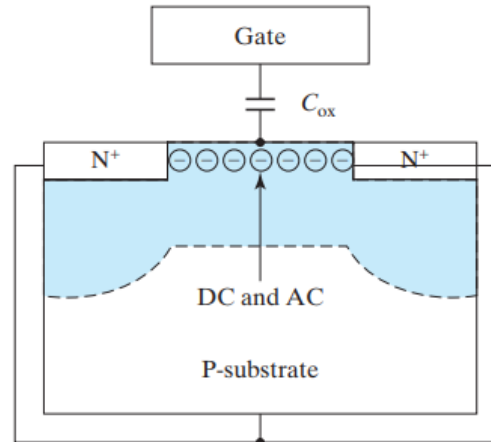
$$\frac{1}{C} = \frac{1}{C_{ox}} + \frac{1}{C_{dep}}$$



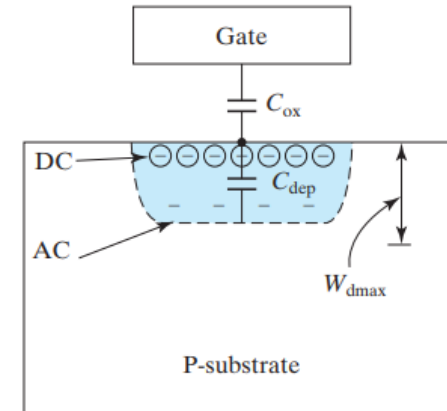
(a)



(b)

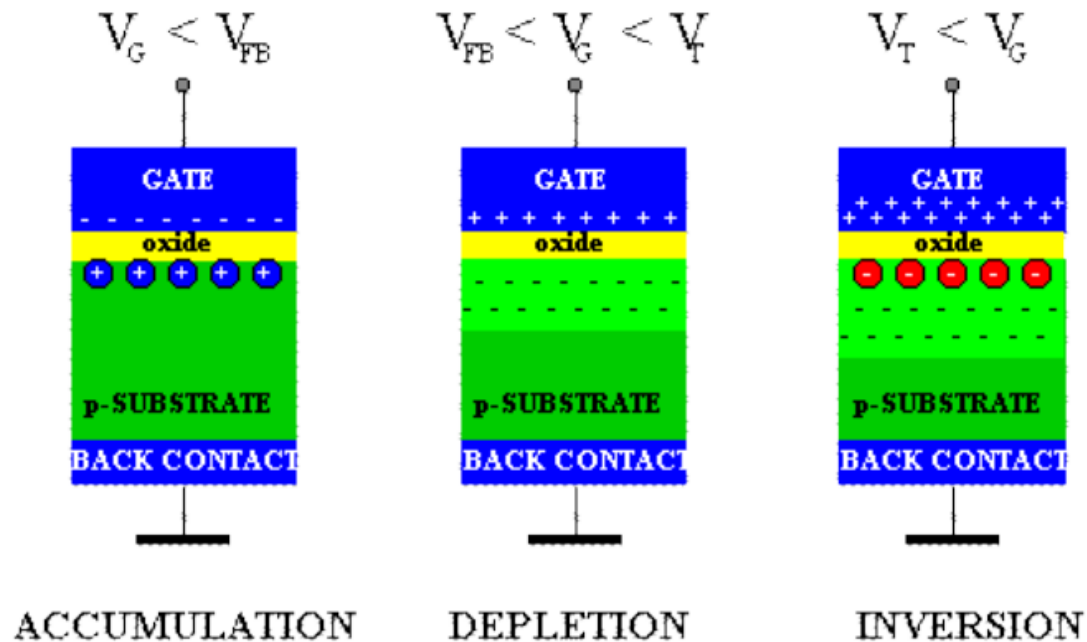


(c)

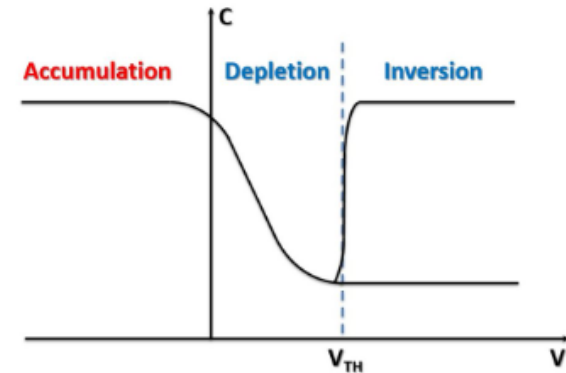


(d)

MOS Capacitors- C-V Characteristics



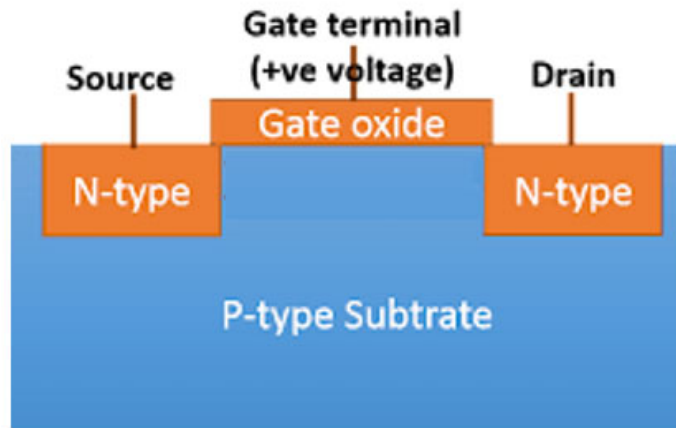
C-V Characteristics



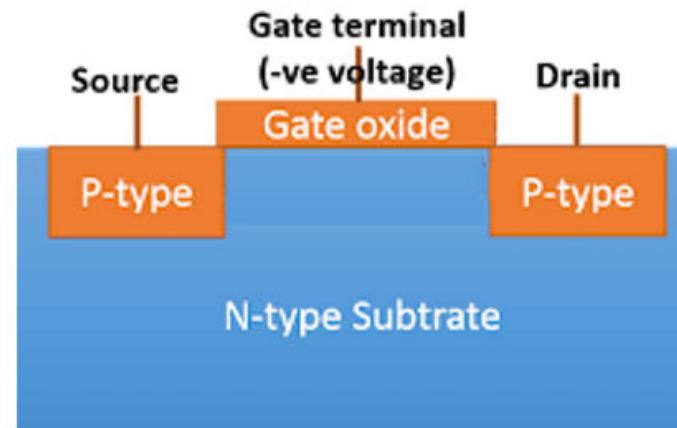
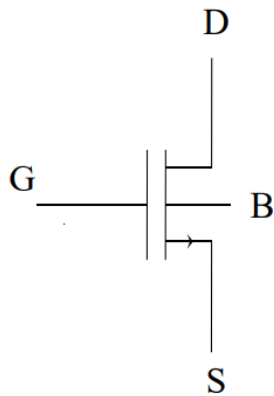
$$C_{dep} = \frac{\epsilon_s}{W_{dep}}$$

$$\frac{1}{C} = \frac{1}{C_{ox}} + \frac{1}{C_{dep}}$$

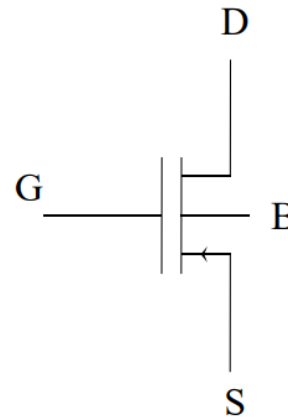
Review of MOSFETs



n-channel MOS
Transistor



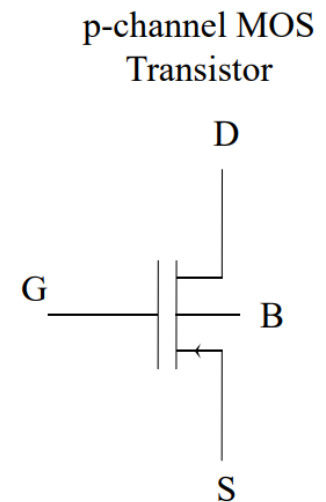
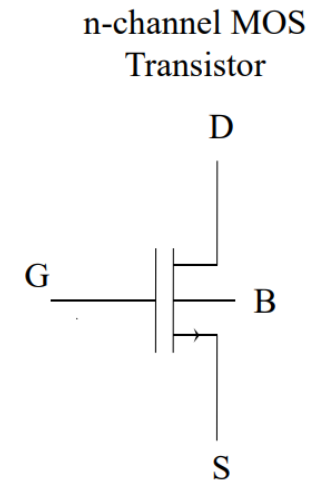
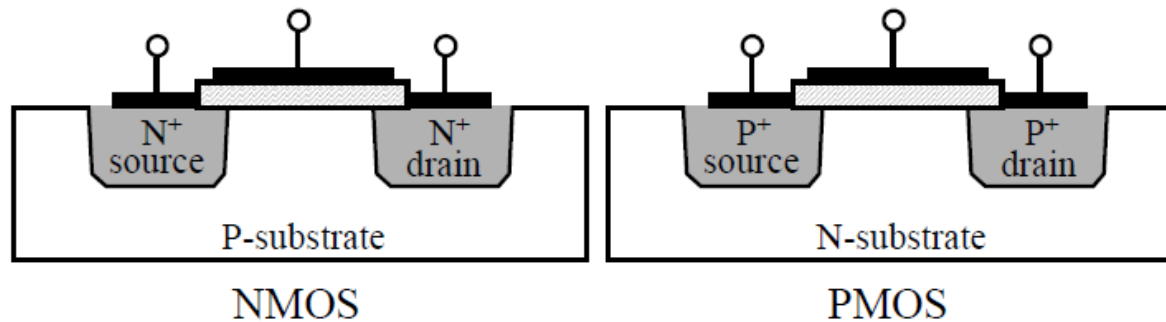
p-channel MOS
Transistor



Review of MOSFETs

MOS Transistor

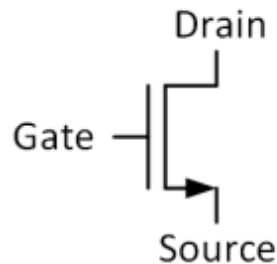
- Add “source” and “drain” terminals to MOS capacitor
- Transistor types
 - NMOS: p-type substrate, n⁺ source/drain
 - PMOS: n-type substrate, p⁺ source/drain



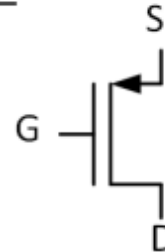
Review of MOSFETs

- We now turn our attention to another type of transistor, the **MOSFET**:
 - ▣ **M**etal **O**xide **S**emiconductor **F**ield **E**ffect **T**ransistor
- Many similarities to the BJT:
 - ▣ Three terminals
 - ▣ Voltage at one terminal controls current between the other two
 - A transconductance device
 - ▣ Two polarities: N-channel and P-channel MOSFETS
 - Our focus will primarily be N-channel MOSFETs (NMOS devices)

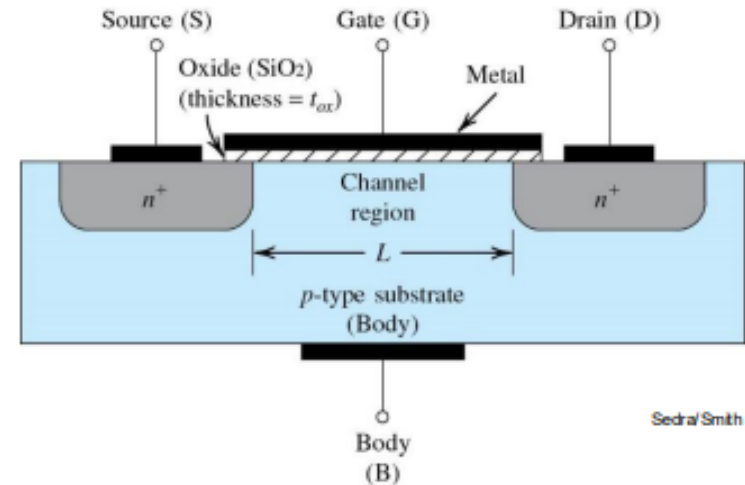
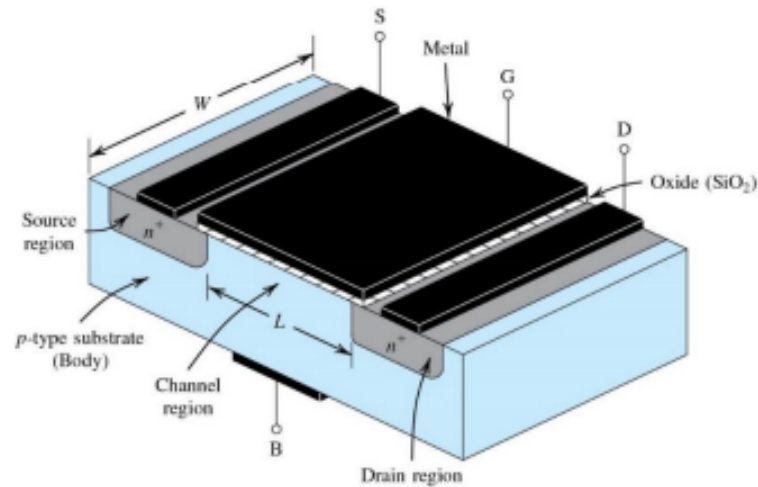
N-Channel
(NMOS):



P-Channel
(PMOS):



Review of MOSFETs



- P-type substrate
- N+ source and drain
- **Metal gate electrode**, and source/drain/body contacts
- Thin **oxide** insulates the gate from the rest of the device
- Region of substrate between the drain and source is the **channel**
 - Channel dimensions: W and L

Review of MOSFETs

- Terminal voltages and currents named as shown
 - ▣ Again, lower-case v/i and upper-case subscript represents **total** (AC and DC) voltage and current
- For an NMOS device in typical operation:

$$v_{GS} \geq 0$$

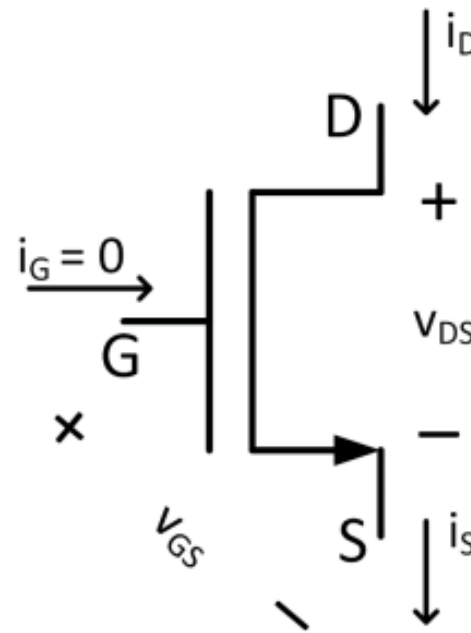
$$v_{DS} \geq 0$$

- Gate oxide does not allow current to flow, so

$$i_G = 0$$

and

$$i_D = i_S$$



Review of MOSFETs

Cut-Off Region

- Gate and source both grounded

$$v_{GS} = 0$$

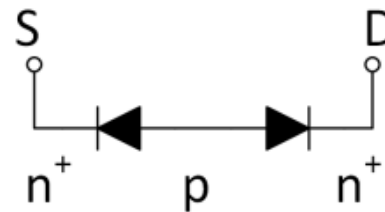
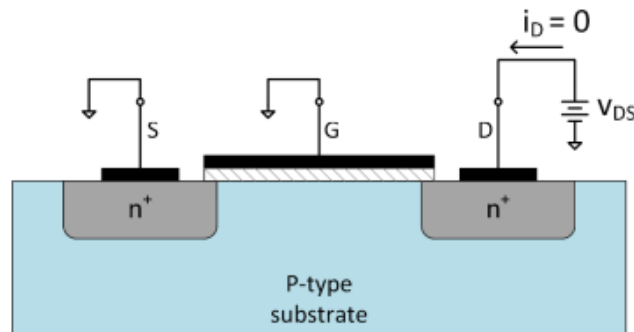
- Drain-to-source pathway looks like two back-to-back diodes

- Very high drain-source resistance ($r_{DS} = \infty$)

- Even for $v_{DS} > 0$, no current will flow

$$i_D = 0$$

- Looks like an open switch



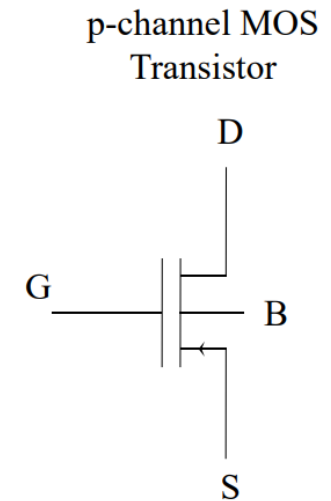
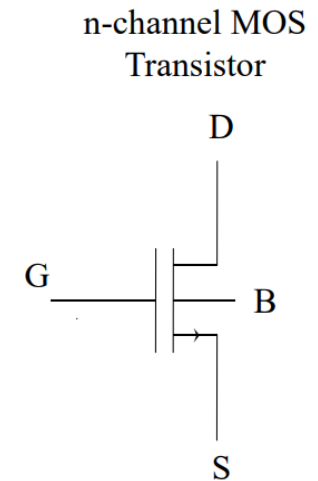
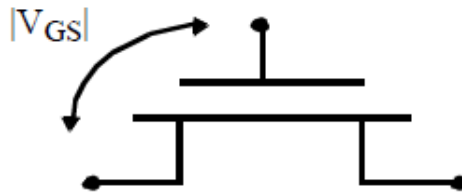
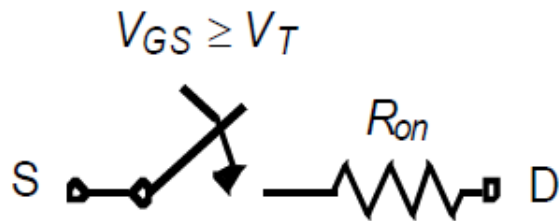
Review of MOSFETs

What is a Transistor?

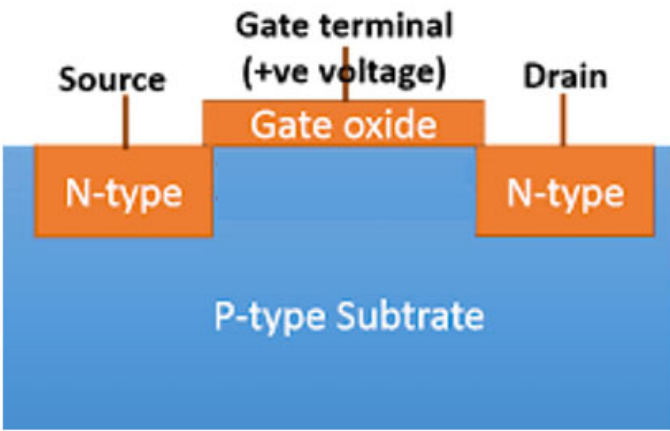
A Switch!



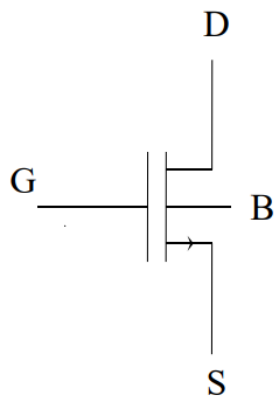
An MOS Transistor



Review of MOSFETs

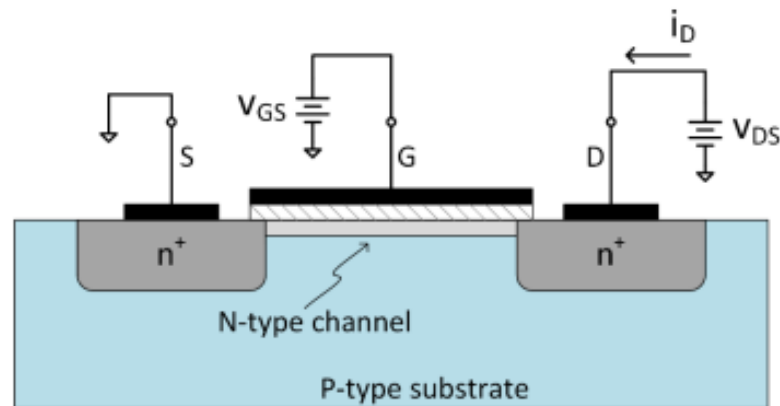


n-channel MOS
Transistor



Review of MOSFETs

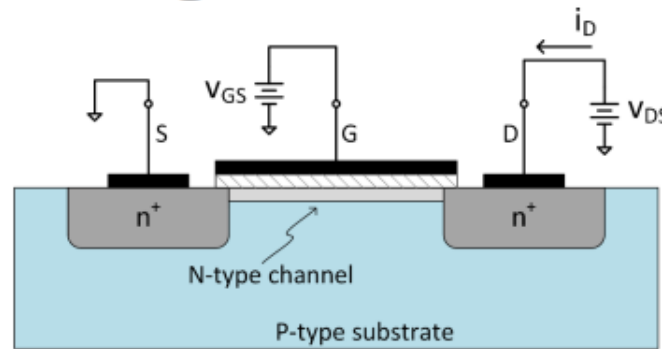
Inversion



- Now, v_{GS} is increased, while v_{DS} is kept small
 - ▣ Electric field established across gate oxide
 - ▣ Holes in p-type substrate repelled deeper into substrate
 - ▣ Electrons from drain and source attracted to region below the gate
- For large enough v_{GS} , p-type material below the gate is ***inverted*** to n-type
 - ▣ An ***inversion layer***
 - ▣ ***Induced n-type channel connects drain to source***
 - ▣ Now, current can flow in response to v_{DS} , $i_D > 0$

Review of MOSFETs

Threshold Voltage



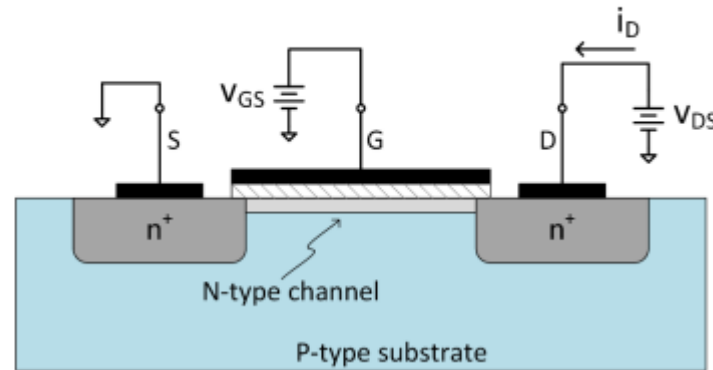
- Channel is induced once v_{GS} exceeds a certain voltage:
 - ▣ The **threshold voltage**

$$v_{GS} \geq V_t$$

- ▣ A device parameter
 - ▣ Typically, $V_t = 300\text{ mV} \dots 1\text{ V}$
- As v_{GS} increases beyond V_t , the induced channel gets deeper
- As long as v_{DS} is small ($v_{DS} \ll V_t$), channel depth is uniform

Review of MOSFETs

Overdrive Voltage

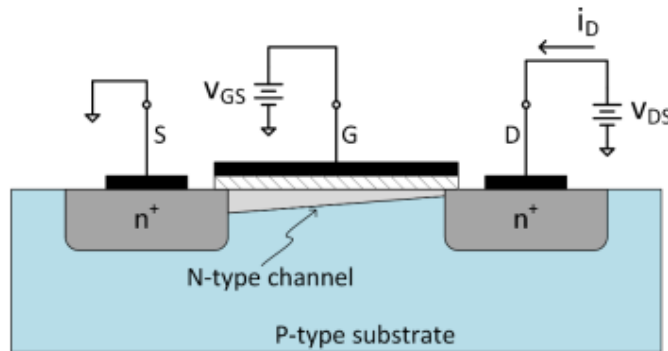


- A channel is induced once v_{GS} exceeds the threshold voltage
- v_{GS} in excess of the threshold voltage is called the **overdrive voltage** or **effective voltage**:

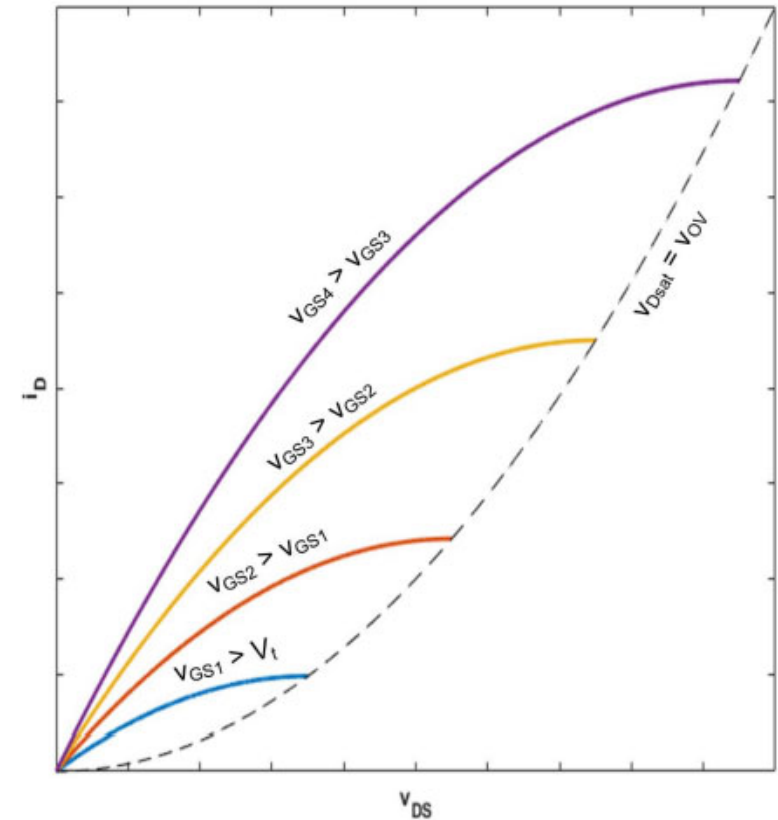
$$v_{OV} = v_{GS} - V_t$$

- As we will soon see, v_{OV} plays an important role in determining device behavior

Review of MOSFETs- Linear Region



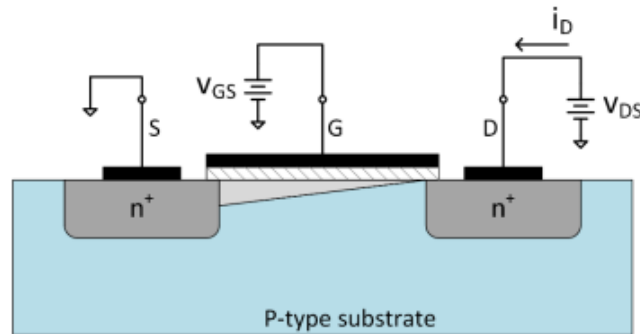
- As v_{DS} increases:
 - ▣ Voltage varies along the channel
 - v_S near the source, v_D near the drain
 - ▣ Gate-to-channel voltage decreases closer to the drain
 - ▣ Channel depth decreases closer to the drain
 - Channel is tapered
- More current flows with increasing v_{DS} , but channel resistance increases as channel becomes more tapered



I
S

Review of MOSFETs- Linear Region

Channel Pinch-Off



- Eventually, for large enough v_{DS}
 - ▣ Gate-to-channel voltage near the drain no longer exceeds V_t
 - ▣ Channel **pinch-off** occurs
 - ▣ Channel disappears at the edge of the drain
- Pinch-off occurs when:

$$v_{GD} = V_t = v_{GS} - v_{DS}$$

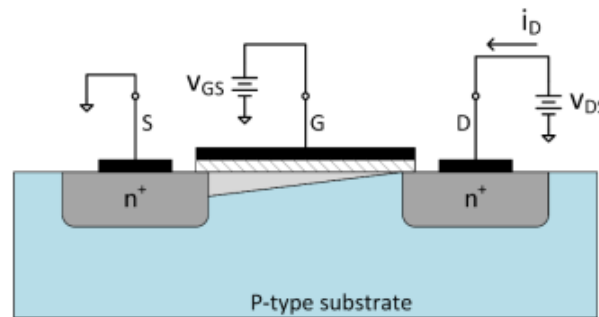
$$v_{DS} = v_{GS} - V_t$$

Review of MOSFETs- Linear Region

Saturation Region

□ Once channel pinch-off occurs:

- Voltage at the drain-end of the channel remains v_{OV} , even as v_{DS} increases
- Any increase in v_{DS} beyond v_{OV} is dropped across the depletion region surrounding the drain
- Voltage across the length of the channel is fixed at v_{OV}
- Pinched-off channel shape does not change with v_{DS}
- Drain current **saturates** at a constant value for constant v_{GS}



Review of MOSFETs

Channel formation basics

- A channel forms when

$$V_{GS} > V_T$$

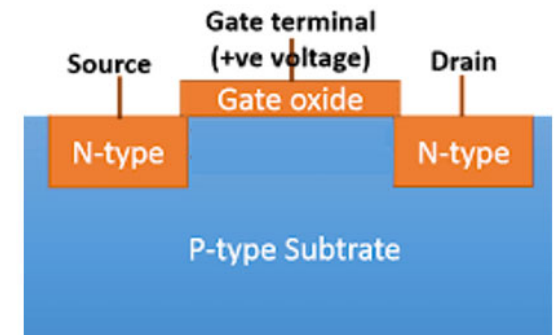
because inversion charge appears under the gate.

- Along the channel, the local inversion charge is

$$Q_n(x) \propto V_{GS} - V_T - V(x),$$

where $V(x)$ is the channel potential at position x .

- At the source end, $V(0) = 0 \implies Q_n(0) \propto V_{GS} - V_T$ (strong channel).
- At the drain end, $V(L) = V_{DS} \implies Q_n(L) \propto V_{GS} - V_T - V_{DS}$.



Review of MOSFETs

Condition for pinch-off

- If $V_{DS} < V_{GS} - V_T$:

Channel charge is positive all along the channel → continuous inversion path from source to drain. MOSFET is in **linear/triode region**.

- If $V_{DS} = V_{GS} - V_T$:

At the **drain end**,

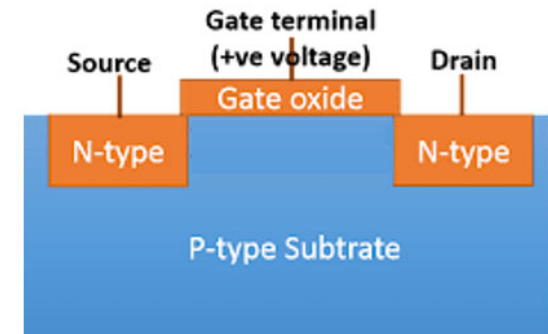
$$Q_n(L) = 0$$

→ the inversion channel just disappears at the drain edge → **onset of pinch-off**.

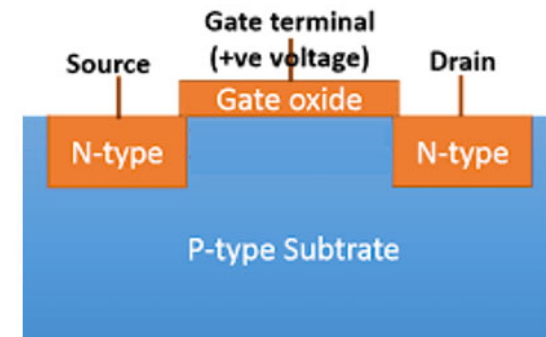
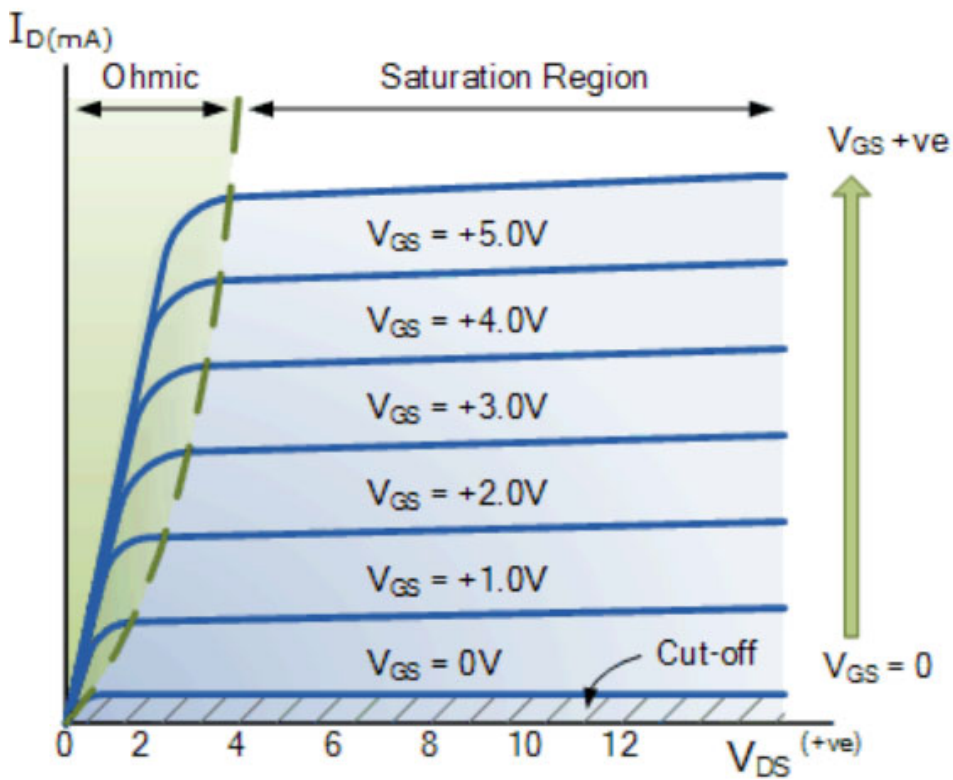
- If $V_{DS} > V_{GS} - V_T$:

No inversion possible near the drain. Instead:

- Channel terminates at a "pinch-off point" before the drain.
- Beyond this, a depletion region carries the extra potential drop.
- Current saturates since the effective voltage across the channel is clamped at $V_{GS} - V_T$.



Review of MOSFETs

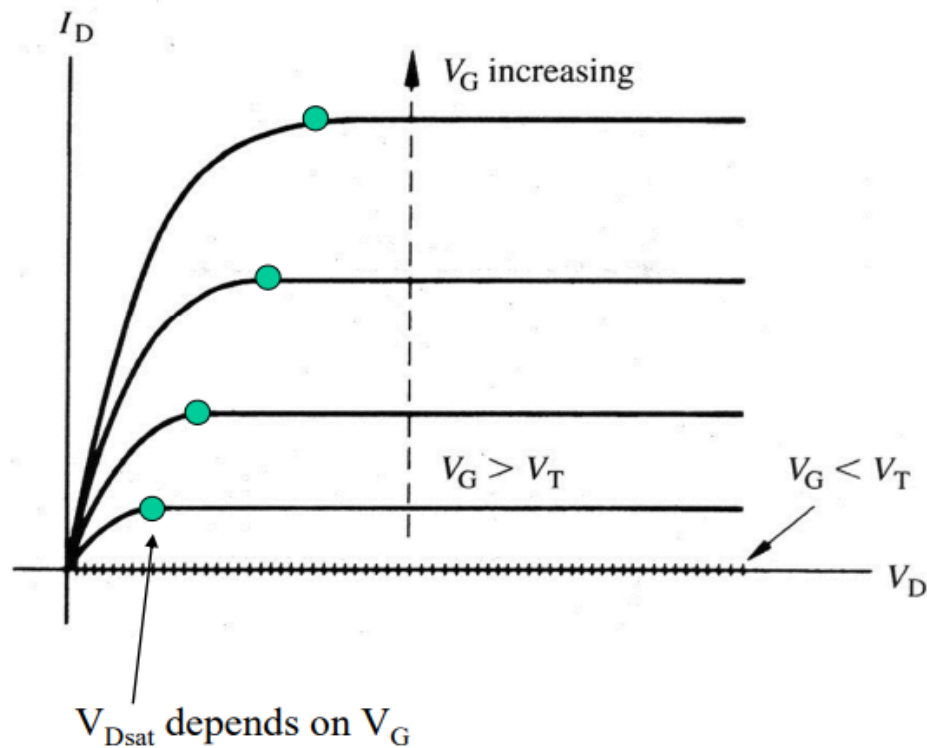


Relation between V_{DS} & V_{GS}

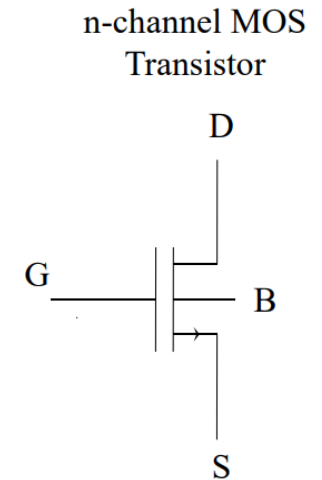
Case	V_T	Channel condition
Linear region	$V_{DS} < V_{GS} - V_T$	Continuous inversion from source to drain
Pinch-off onset	$V_{DS} = V_{GS} - V_T$	Channel just disappears at drain end
Saturation	$V_{DS} > V_{GS} - V_T$	Pinch-off near drain, depletion region forms, current saturates

Review of MOSFETs

I_D - V_{DS} curves for various V_{GS} :

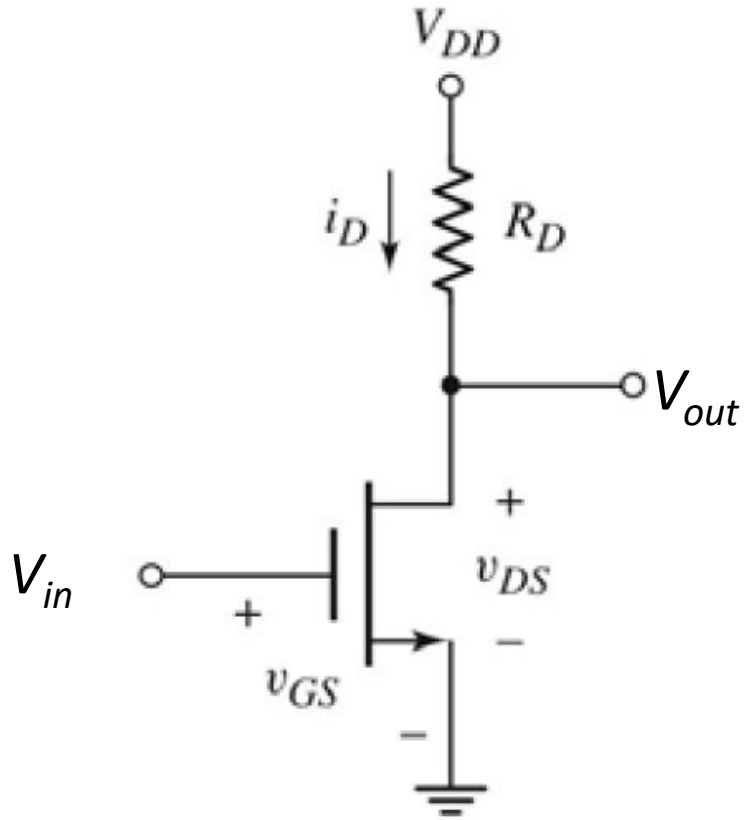


$$\beta = \mu C_{ox} \frac{W}{L}$$

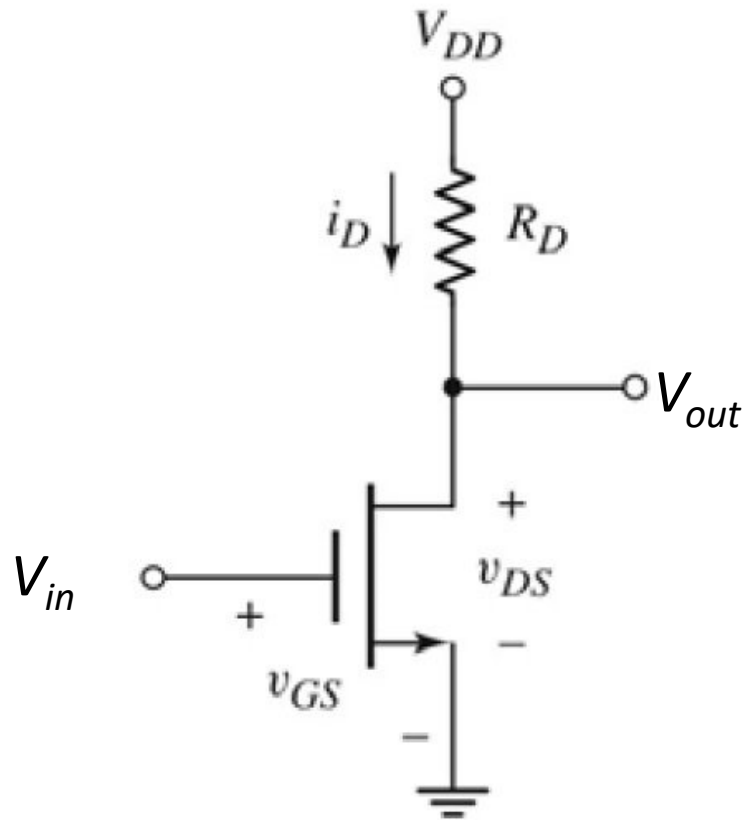


$$I_D = \begin{cases} 0 & V_{gs} < V_t \quad \text{cutoff} \\ \beta \left(V_{gs} - V_t - \frac{V_{ds}}{2} \right) V_{ds} & V_{ds} < V_{dsat} \quad \text{linear} \\ \frac{\beta}{2} (V_{gs} - V_t)^2 & V_{ds} > V_{dsat} \quad \text{saturation} \end{cases}$$

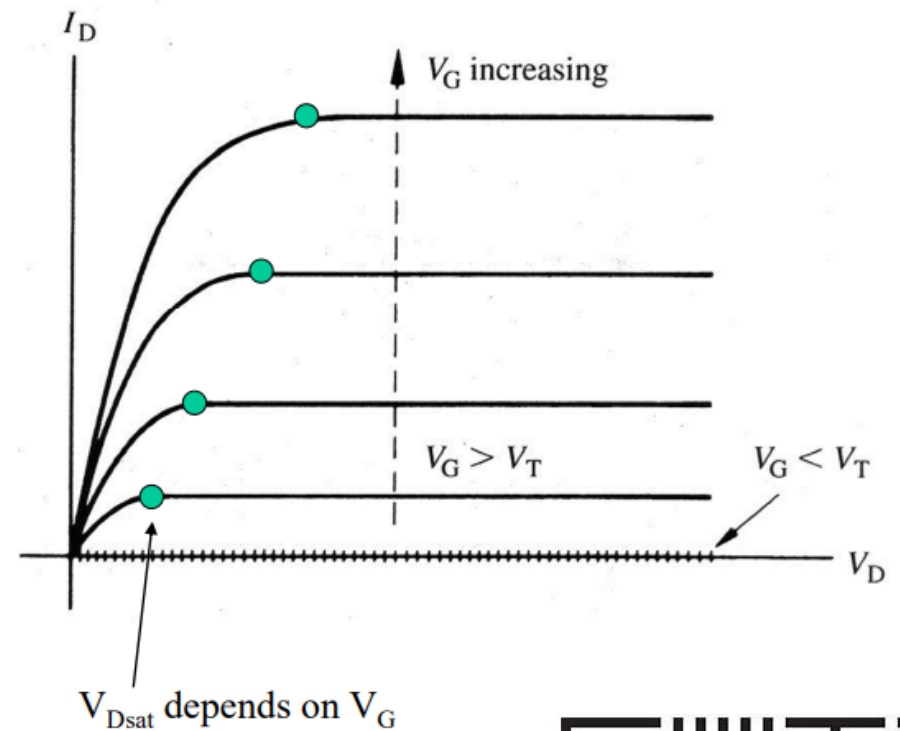
Review of MOSFETs: DC load line of n-MOSFET



Review of MOSFETs: DC load line of n-MOSFET

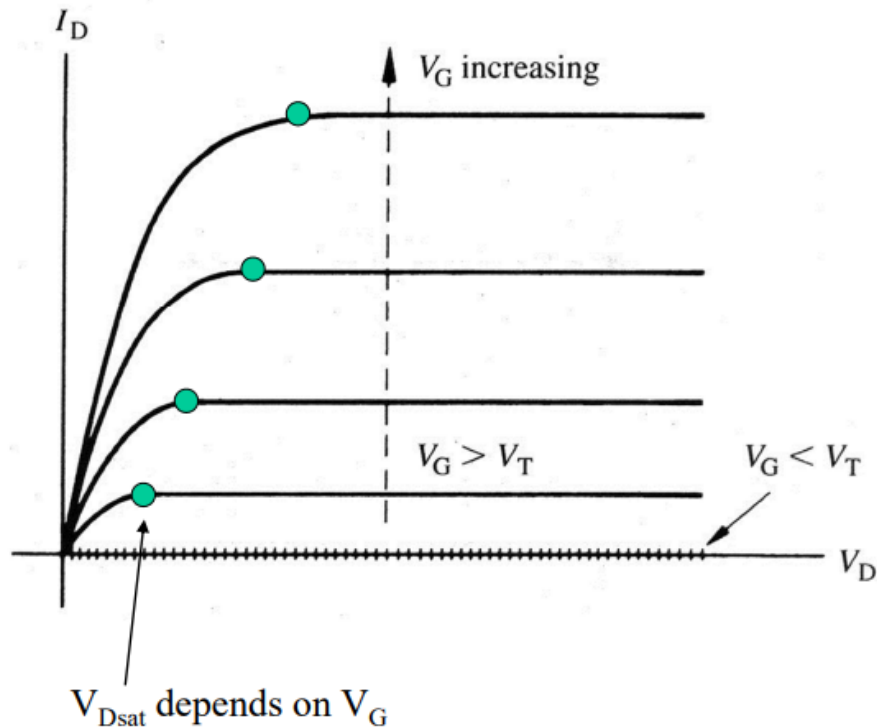


I_D - V_{DS} curves for various V_{GS} :

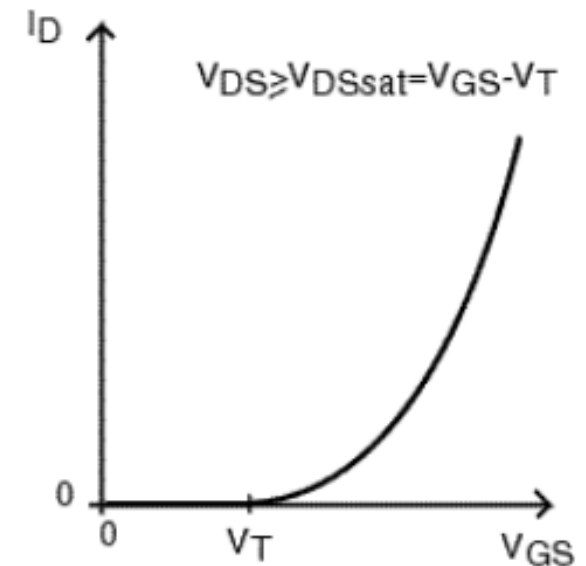


Review of MOSFETs: DC load line of n-MOSFET

I_D - V_{DS} curves for various V_{GS} :

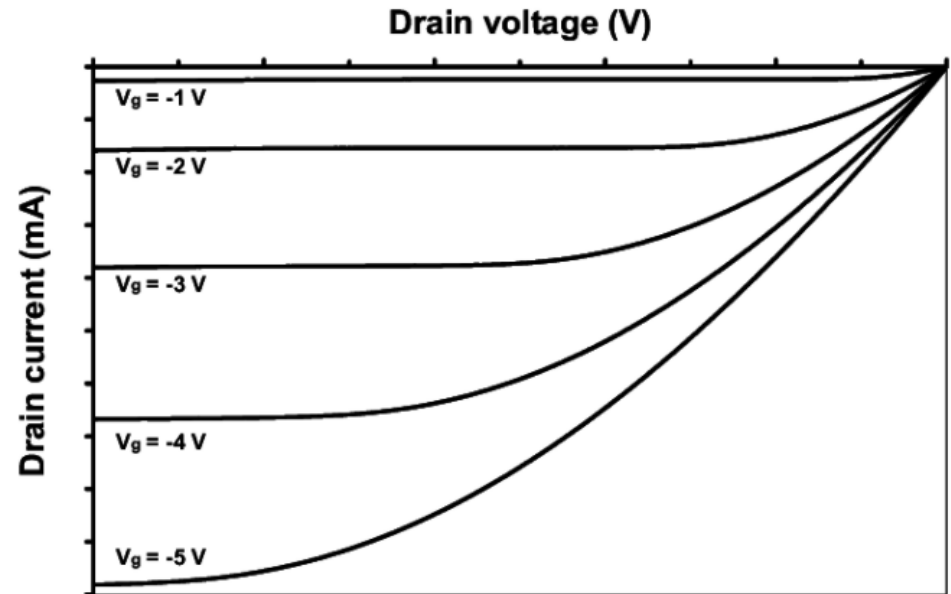
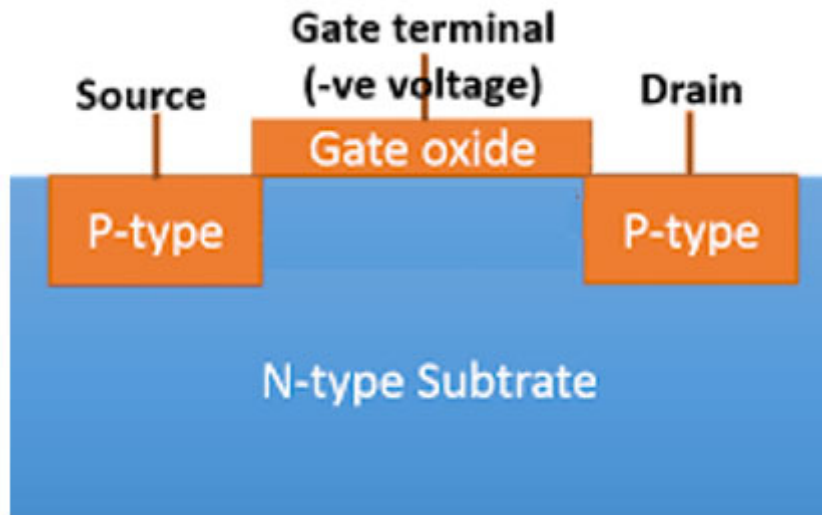


Transfer characteristics:



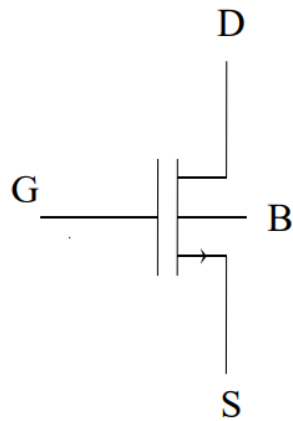
Review of MOSFETs

p-MOSFET

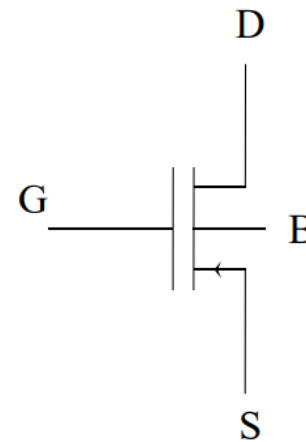


Review of MOSFETs

n-channel MOS
Transistor

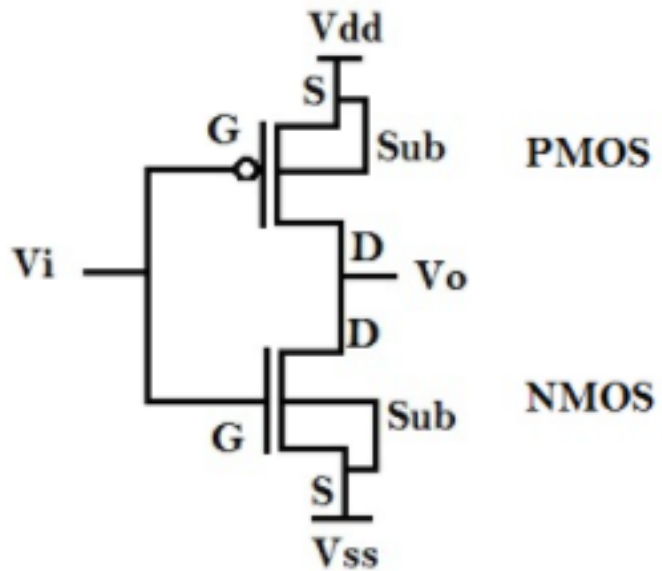


p-channel MOS
Transistor



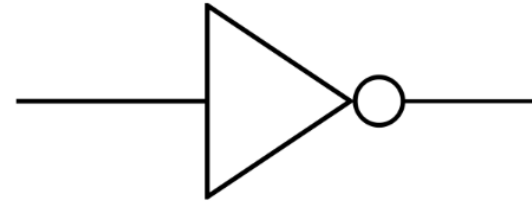
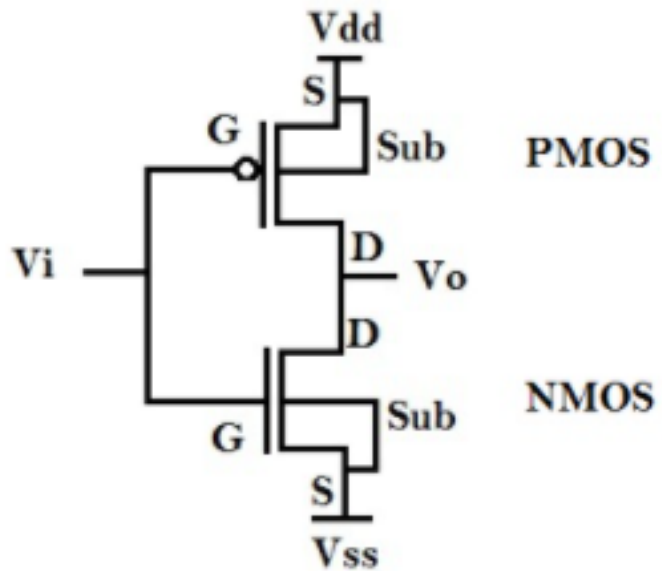
MOSFET type	$V_{GS} = +ve$	$V_{GS} = 0$	$V_{GS} = -ve$
N-Channel	ON	OFF	OFF
P-Channel	OFF	OFF	ON

CMOS circuit

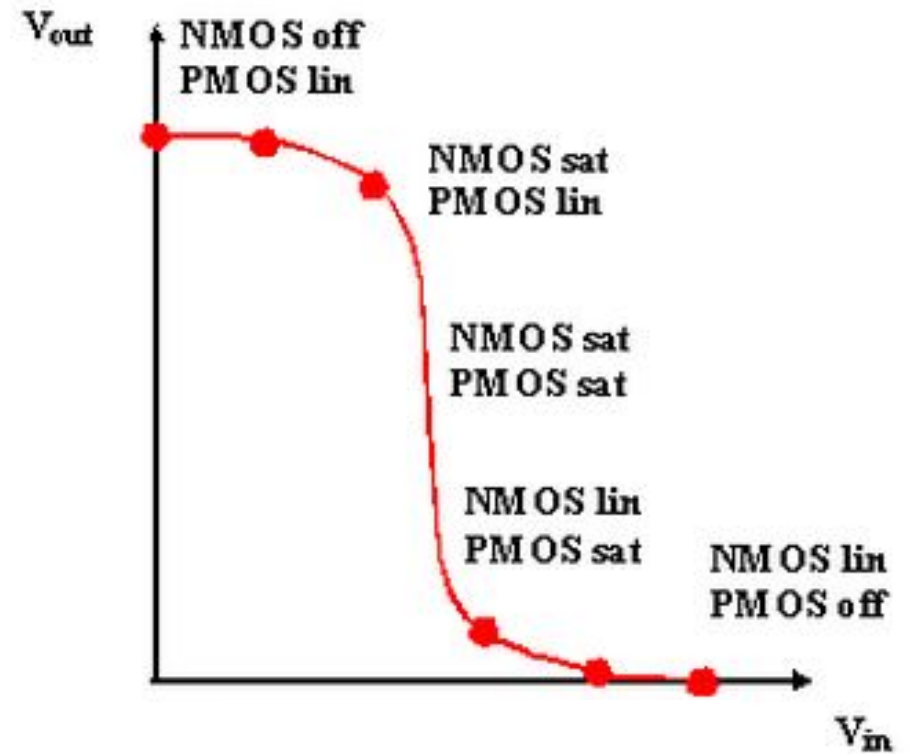
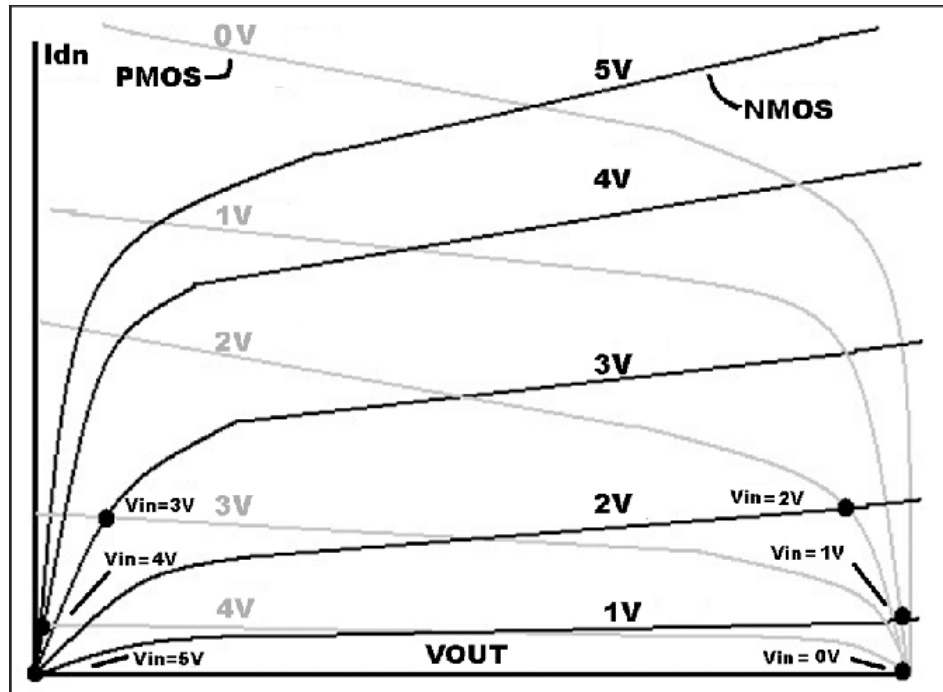


G = Gate Terminal
S = Source Terminal
D = Drain Terminal
Sub = Substrate Terminal

CMOS circuit



CMOS circuit



CMOS circuit: Noise Margin

- Noise margin is the ratio by which the signal exceeds the minimum acceptable amount.
- It explains up to what extent IC allows noise in the transmission of logic '0' and logic '1'.
- Logic '0' and '1' – represent the range of input values
- Hence, for error free digital signal transmission noise margin is required

CMOS circuit: Noise Margin

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